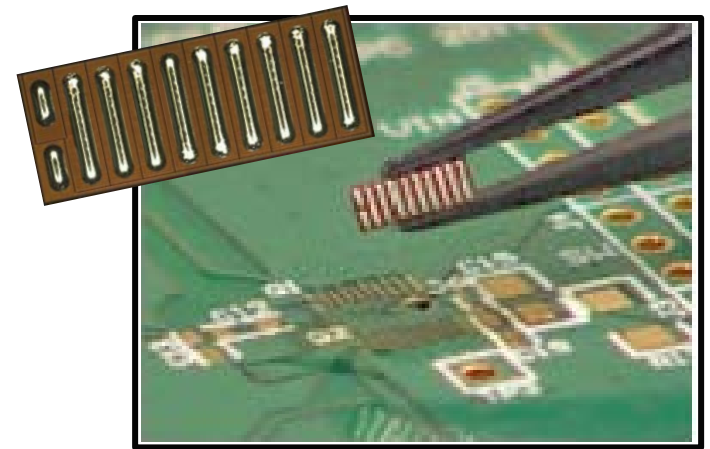


GaN is Crushing Silicon



- How eGaN[®] FETs work
- Hard Switched DC-DC converters
 - High Efficiency point-of-load converter
 - Envelope Tracking buck converter
- Resonant DC-DC Converters
 - Bus Converter
 - ZVS Class D Wireless Power Transmission
- A Look into the Future
- Q & A

eGaN[®] is a registered trademark of Efficient Power Conversion Corporation

Power Switch Wish List

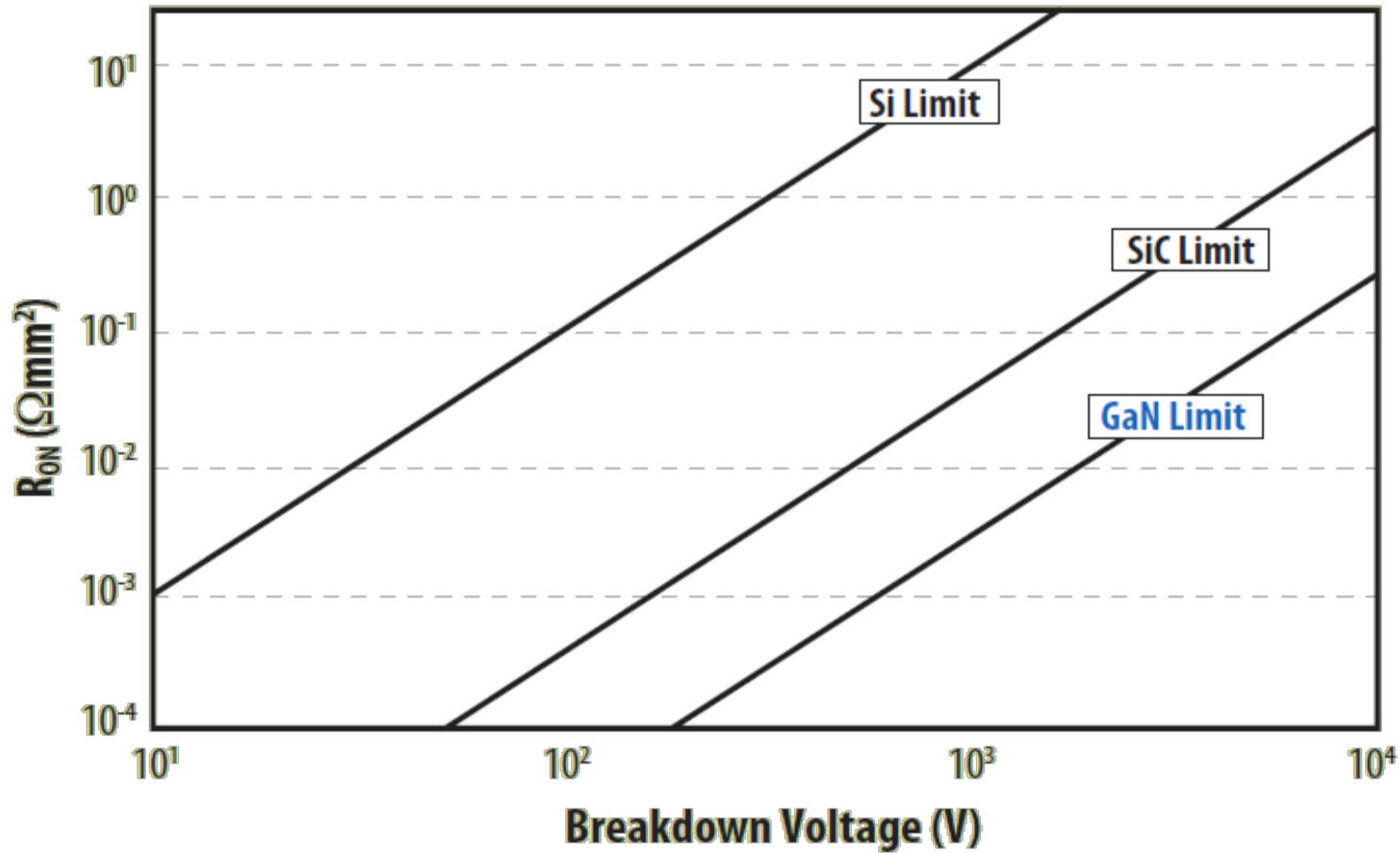


- Lower On Resistance
- Faster
- Less Capacitance
- Smaller
- Lower Cost

Material Comparison

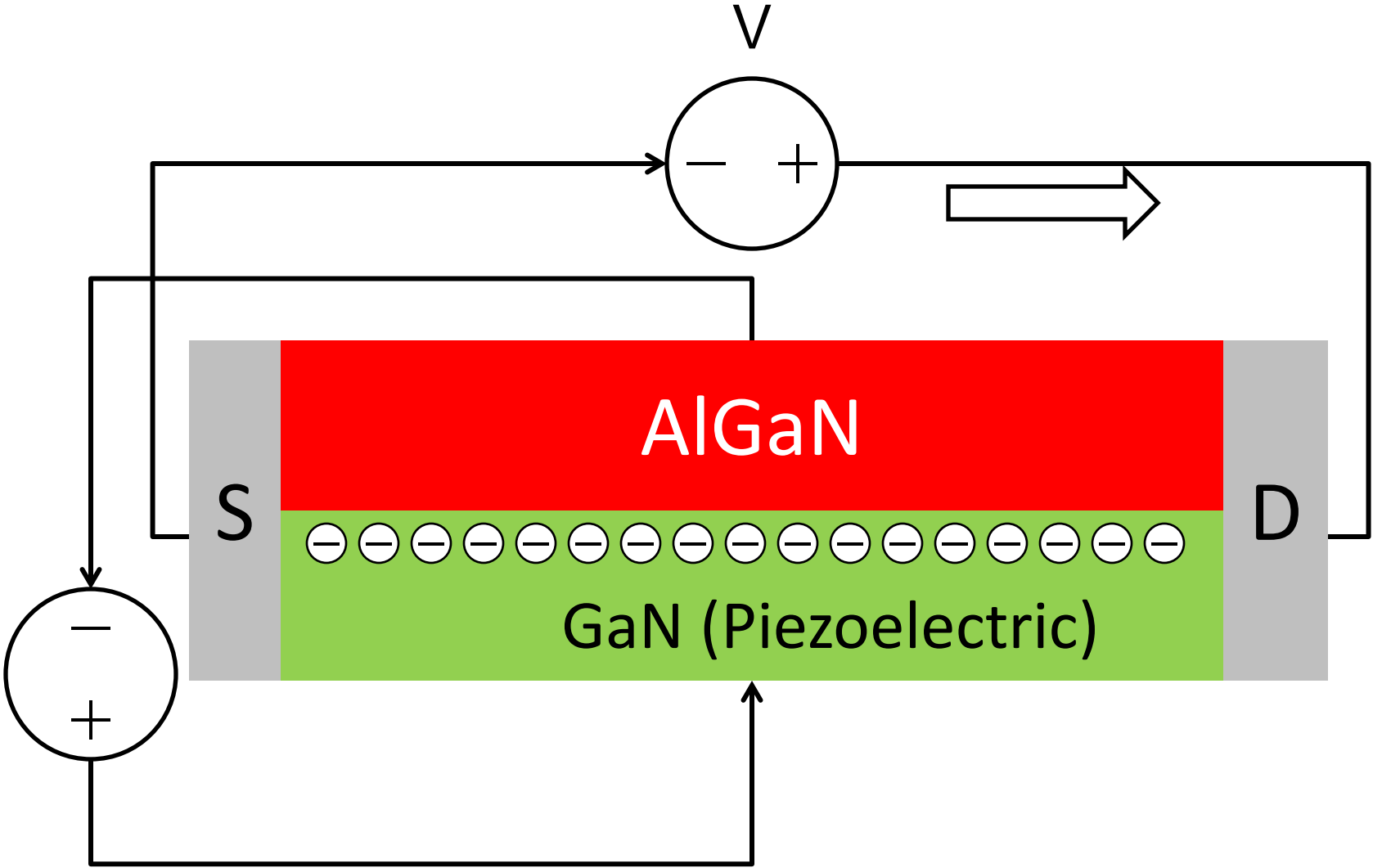
Parameter		GaN	Silicon	SiC
Band Gap E_g	eV	3.2	1.12	3.4
Breakdown Field E_{BV}	MV/cm	3.3	0.3	3.5
Electron Mobility μ_n	$\text{cm}^2/\text{V}\cdot\text{s}$	2000	1500	650

State of the Art

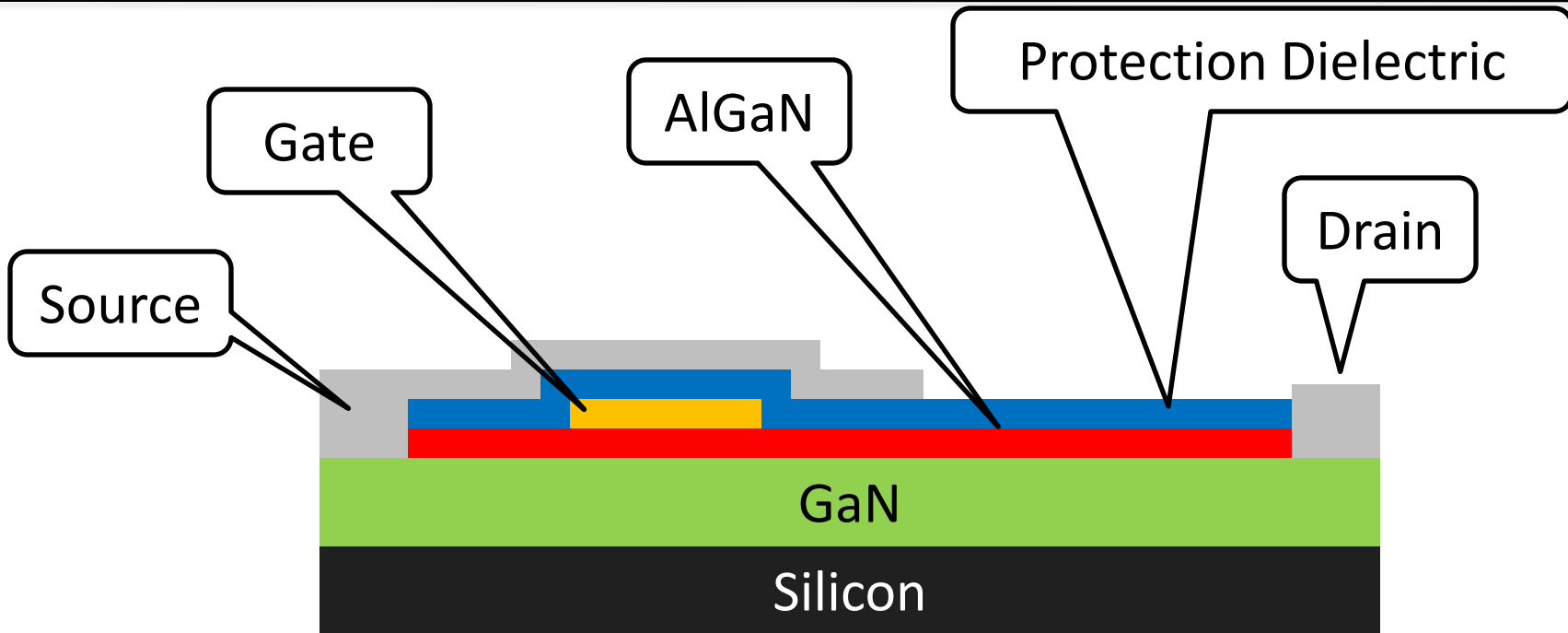


Theoretical on-resistance vs. blocking voltage capability for silicon, silicon carbide, and gallium nitride.

GaN Magic

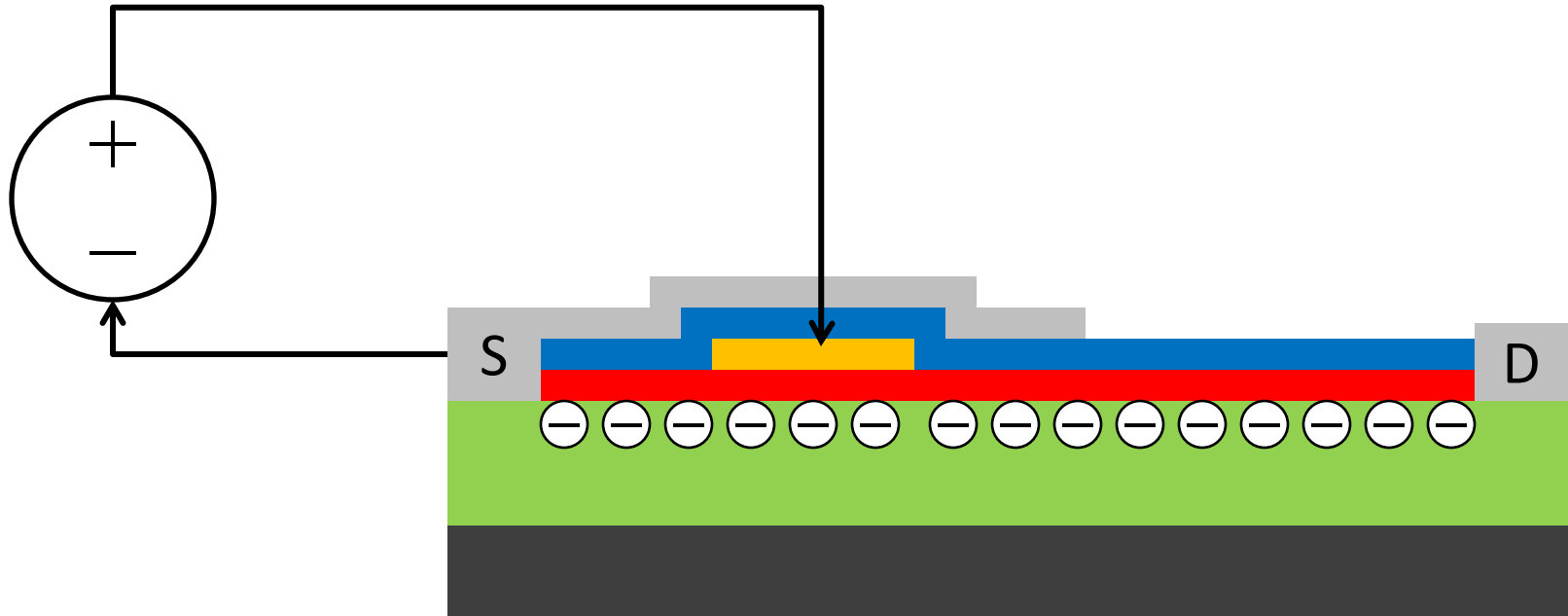


Device Construction Concept



Forms the foundation for a Depletion Mode device

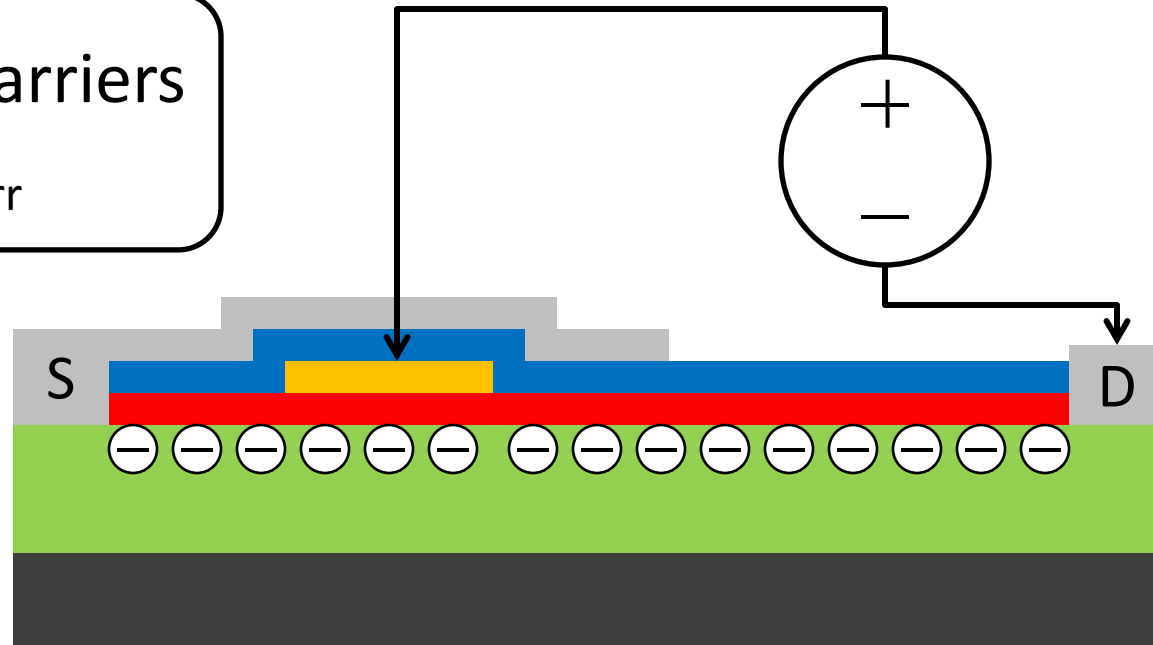
Enhancement Mode – eGaN FET



A positive voltage from Gate-To-Source establishes an electron gas under the gate

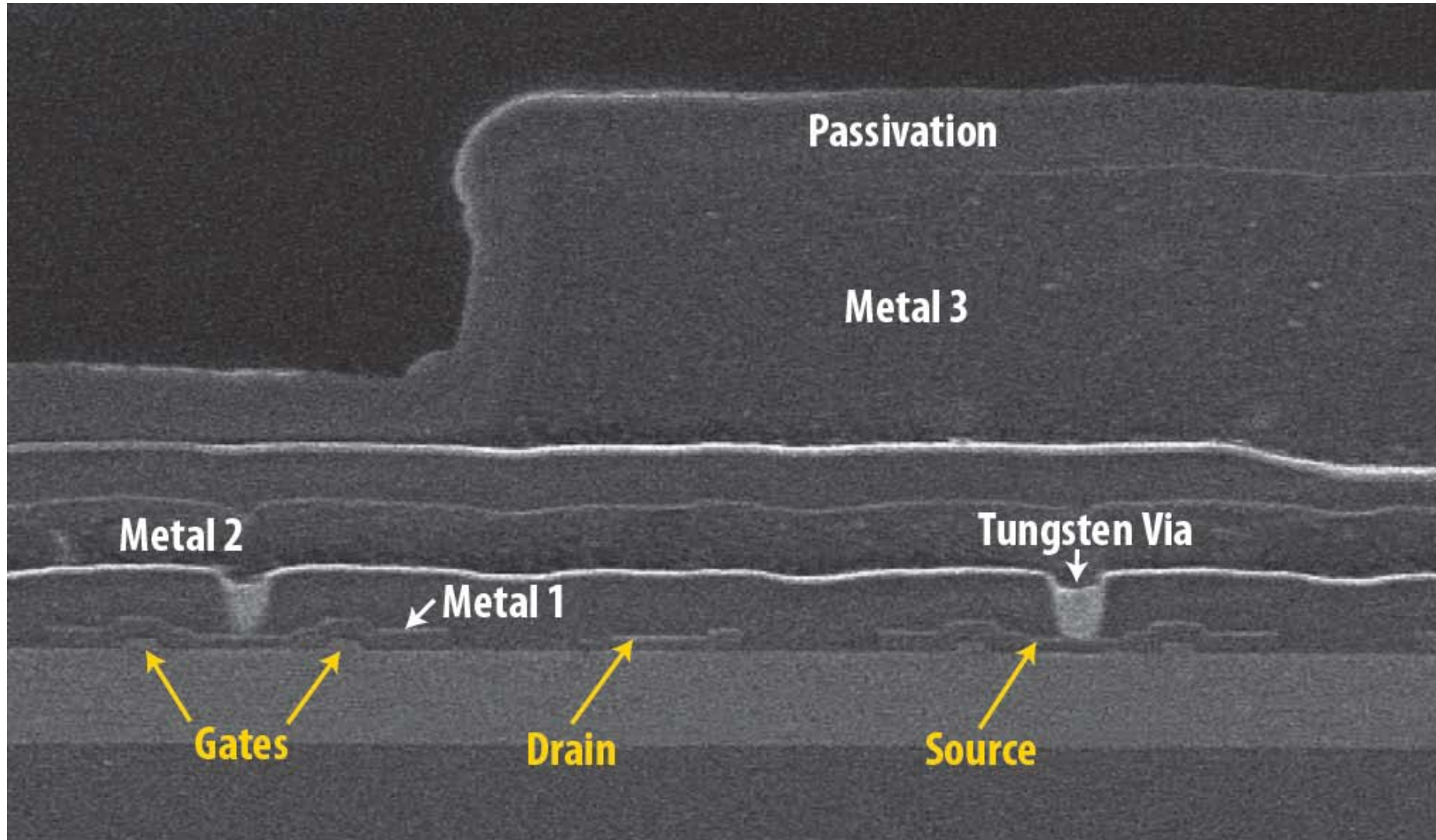
Body Diode?

No Minority Carriers
= Zero Q_{rr}

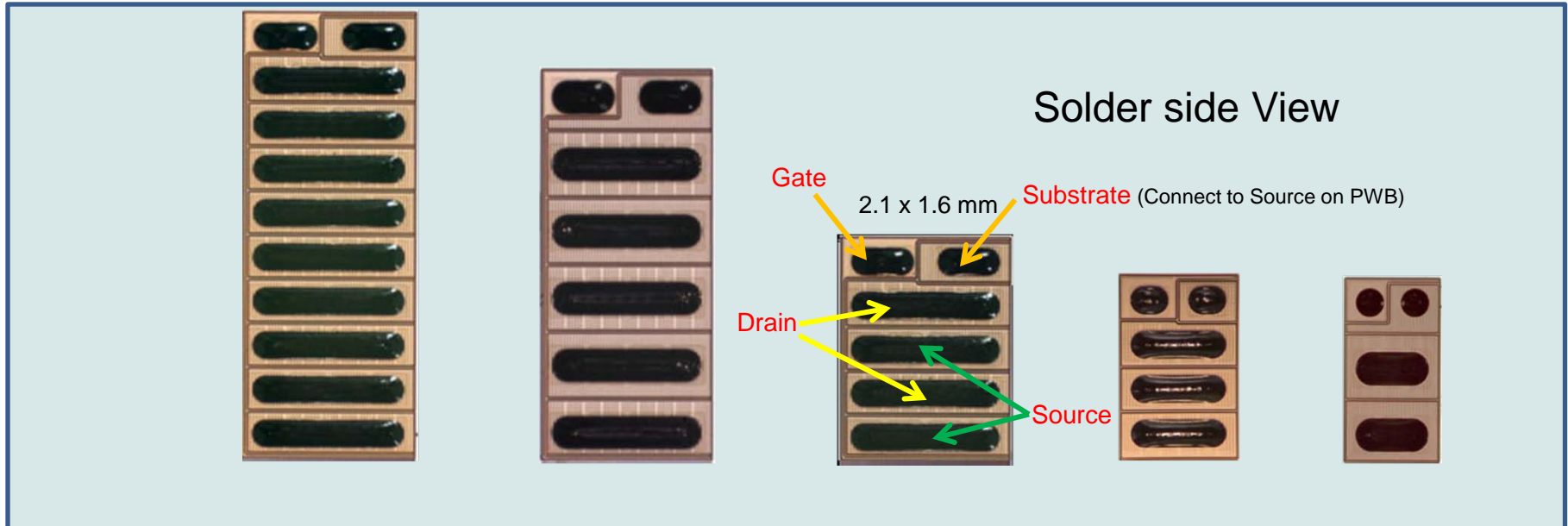


A positive voltage from Gate-To-Drain
also establishes an electron gas under the gate
enabling reverse conduction

Cross Section of an eGaN FET



eGaN FET Low Voltage Product Family



Part Number	Package (mm)	V_{DS} (V)	V_{GS} (V)	$R_{DS(on)}$ @5V (m Ω)	Q_G @5 V Typ. (nC)	Q_{GS} Typ. (nC)	Q_{GD} Typ. (nC)	R_G Typ. (Ω)	V_{th} Typ. (V)	Q_{RR} (nC)	I_D (A)	T_J Max. ($^{\circ}C$)
EPC2015	LGA 4.1x1.6	40	6	4	10.5	3	2.2	0.6	1.4	0	33	150
EPC2014	LGA 1.7x1.1	40	6	16	2.5	0.67	0.48	0.6	1.4	0	10	150
EPC2001	LGA 4.1x1.6	100	6	7	8	2.3	2.2	0.6	1.4	0	25	125
EPC2016	LGA 2.1x1.6	100	6	16	4.1	0.93	0.75	0.6	1.4	0	11	125
EPC2007	LGA 1.7x1.1	100	6	30	2.1	0.5	0.6	0.6	1.4	0	6	125
EPC2010	LGA 3.6x1.6	200	6	25	5	1.3	1.7	0.6	1.4	0	12	125
EPC2012	LGA 1.7x0.9	200	6	100	1.5	0.33	0.57	0.6	1.4	0	3	125

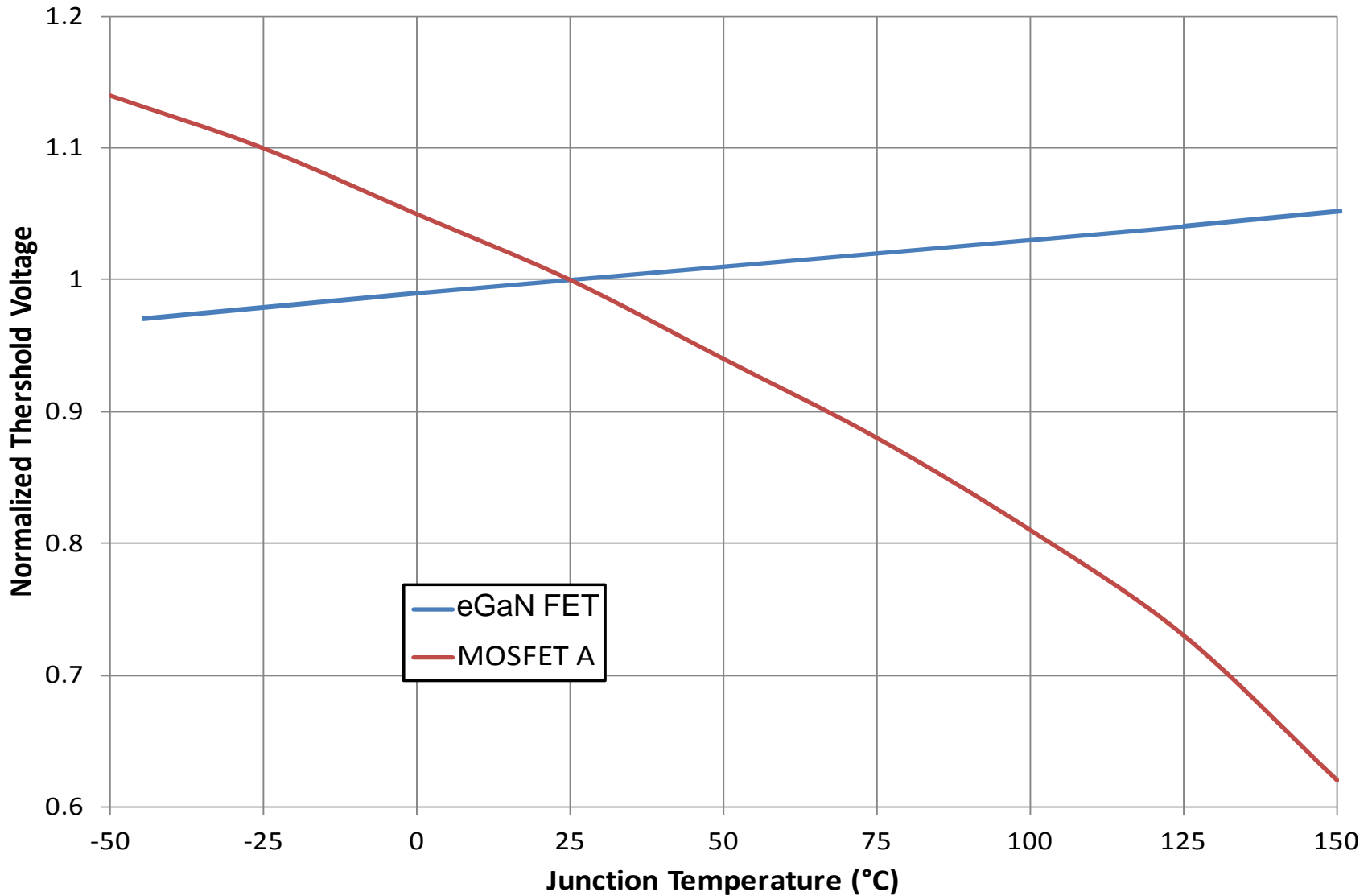
Ultra High Frequency eGaN[®] FETs



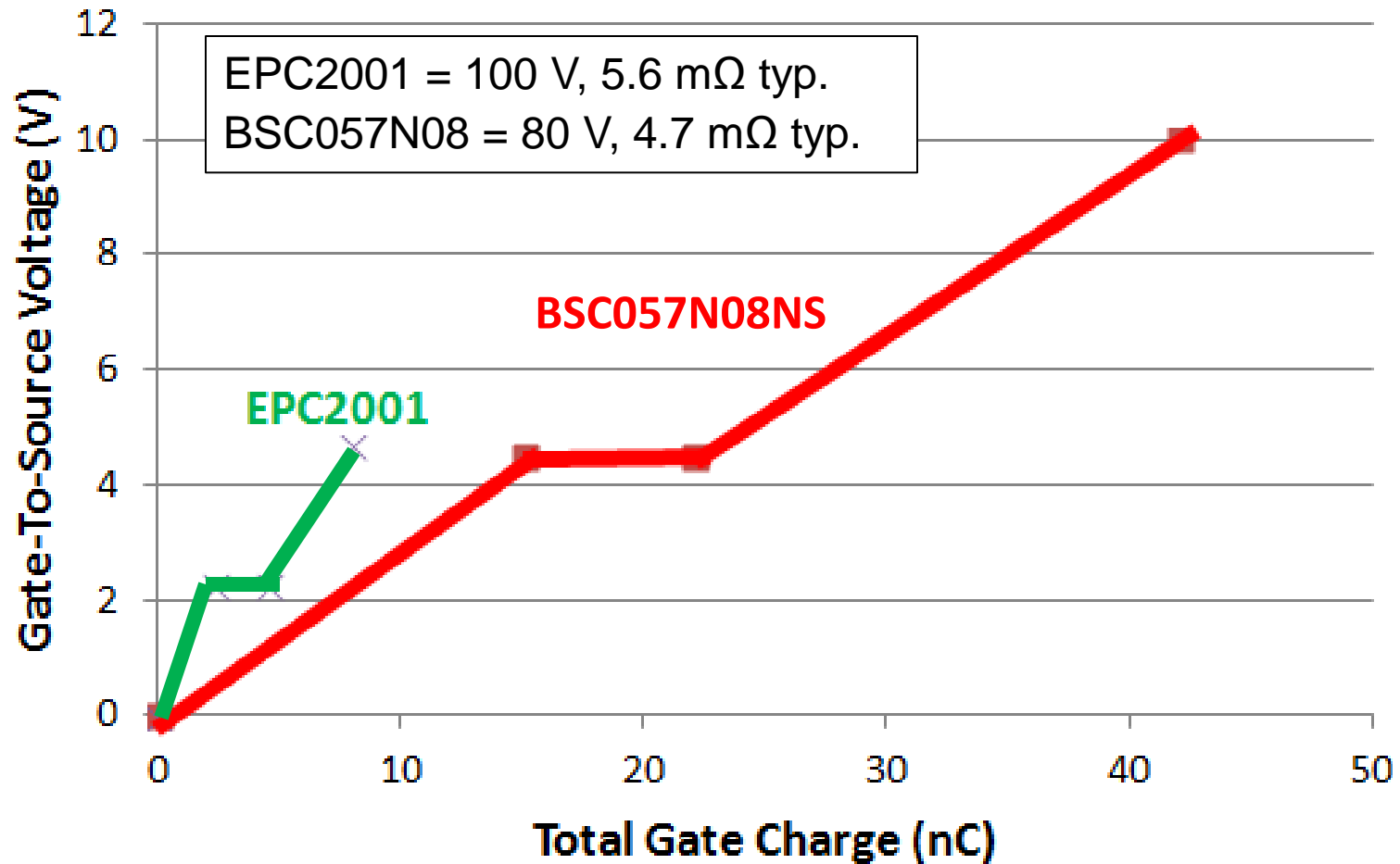
EPC Part No.	BV (V)	Max. R _{DS(ON)} (mΩ) (V _{GS} = 5V, I _D = 0.5 A)	Min. Peak Id (A) (Pulsed, 25 °C, T _{pulse} = 300 μs)	Typical Charge (pC)					Typical Capacitance (pF) (V _{DS} = 20 V; V _{GS} = 0 V)		
				Q _G	Q _{GD}	Q _{GS}	Q _{OSS}	Q _{RR}	C _{ISS}	C _{OSS}	C _{RSS}
EPC8004	40	125	7.5	358	31	110	493	0	45	17	0.4
EPC8007	40	160	6	302	25	97	406	0	39	14	0.3
EPC8008	40	325	2.9	177	12	67	211	0	25	8	0.2
EPC8009	65	138	7.5	380	36	116	769	0	47	17	0.4
EPC8005	65	275	3.8	218	18	77	414	0	29	9.7	0.2
EPC8002	65	530	2	141	9.4	59	244	0	21	5.9	0.1
EPC8003	100	300	5	315	34	110	1100	0	38	18	0.2
EPC8010	100	160	7.5	354	32	109	1509	0	47	18	0.2

* Preliminary Data – Subject to Change without Notice

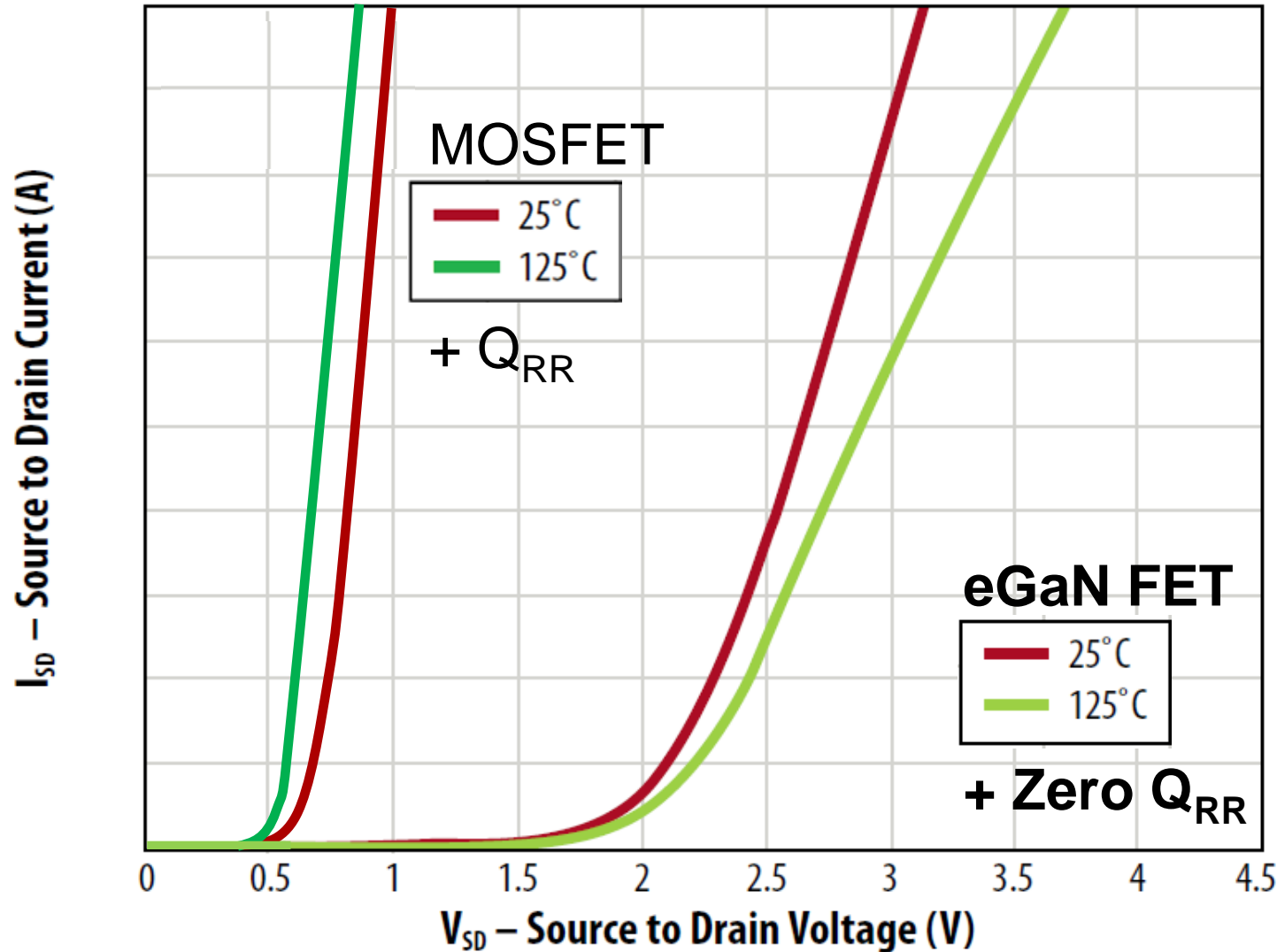
Threshold vs. Temperature



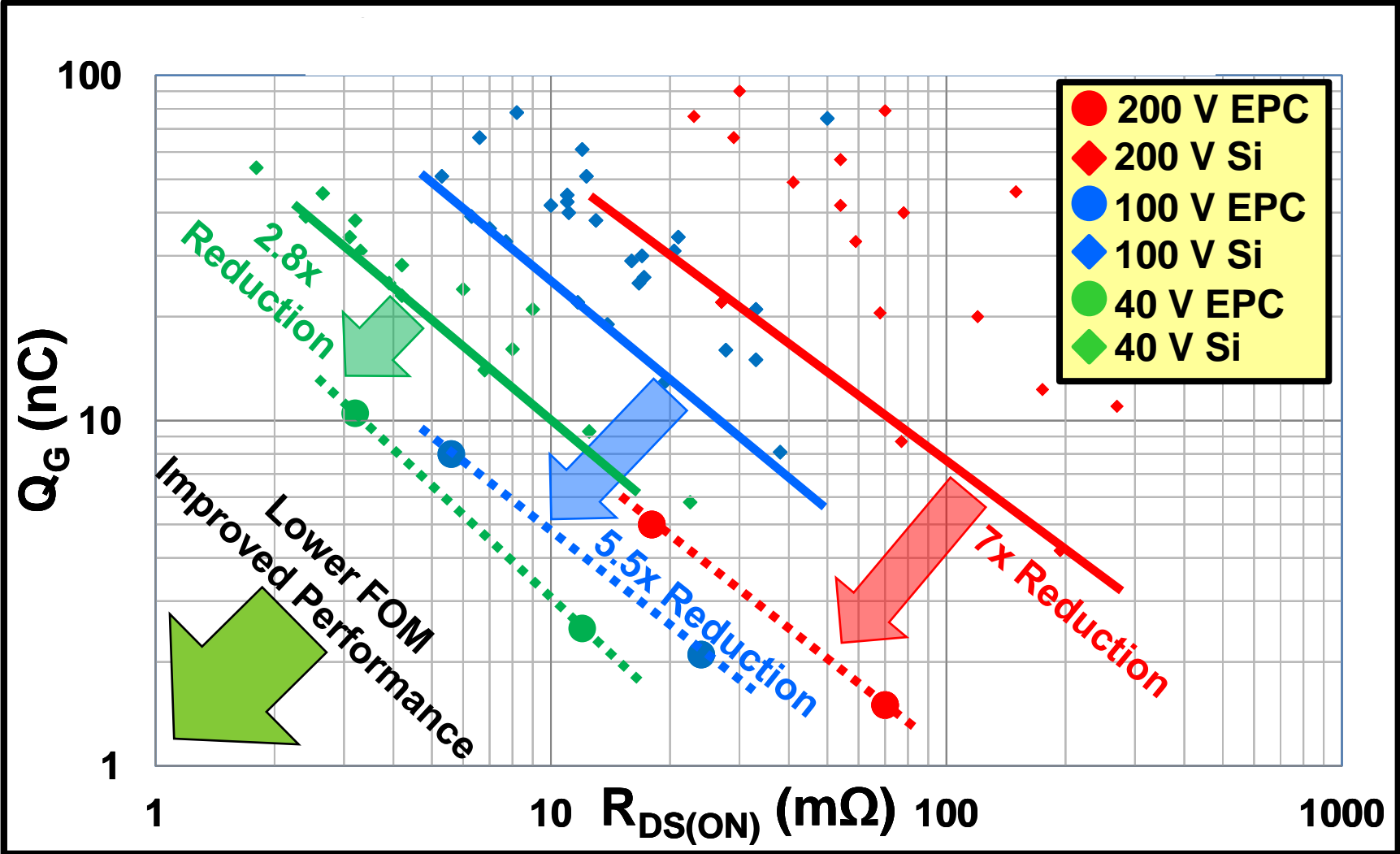
Total Gate Charge



eGaN FET Reverse Conduction



Conduction Figure of Merit



eGaN FET Loss Mechanisms

Like A MOSFET

- I^2R Conduction Loss
- Capacitive Switching Losses
- Gate Drive Losses
- $V \times I$ Switching Loss

Not Like A MOSFET

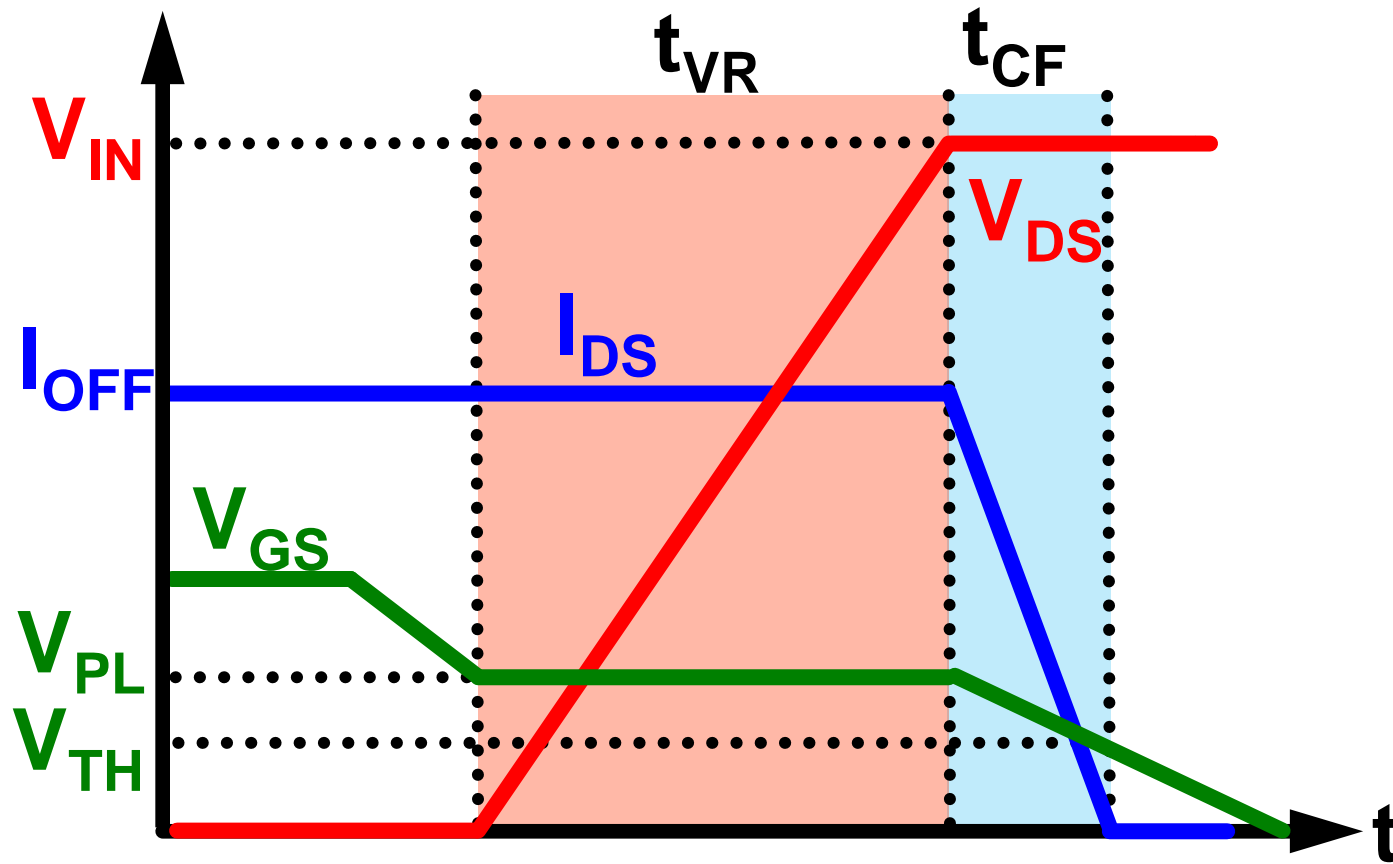
- High Reverse Conduction Loss
- No Body Diode Reverse Recovery Loss

Can be much, much better than
comparable silicon MOSFET

Design Examples

- Hard-Switched DC-DC Conversion
 - Buck Converter
 - Envelope Tracking
- Resonant DC-DC Conversion
 - Resonant Bus Converter
 - Wireless Power

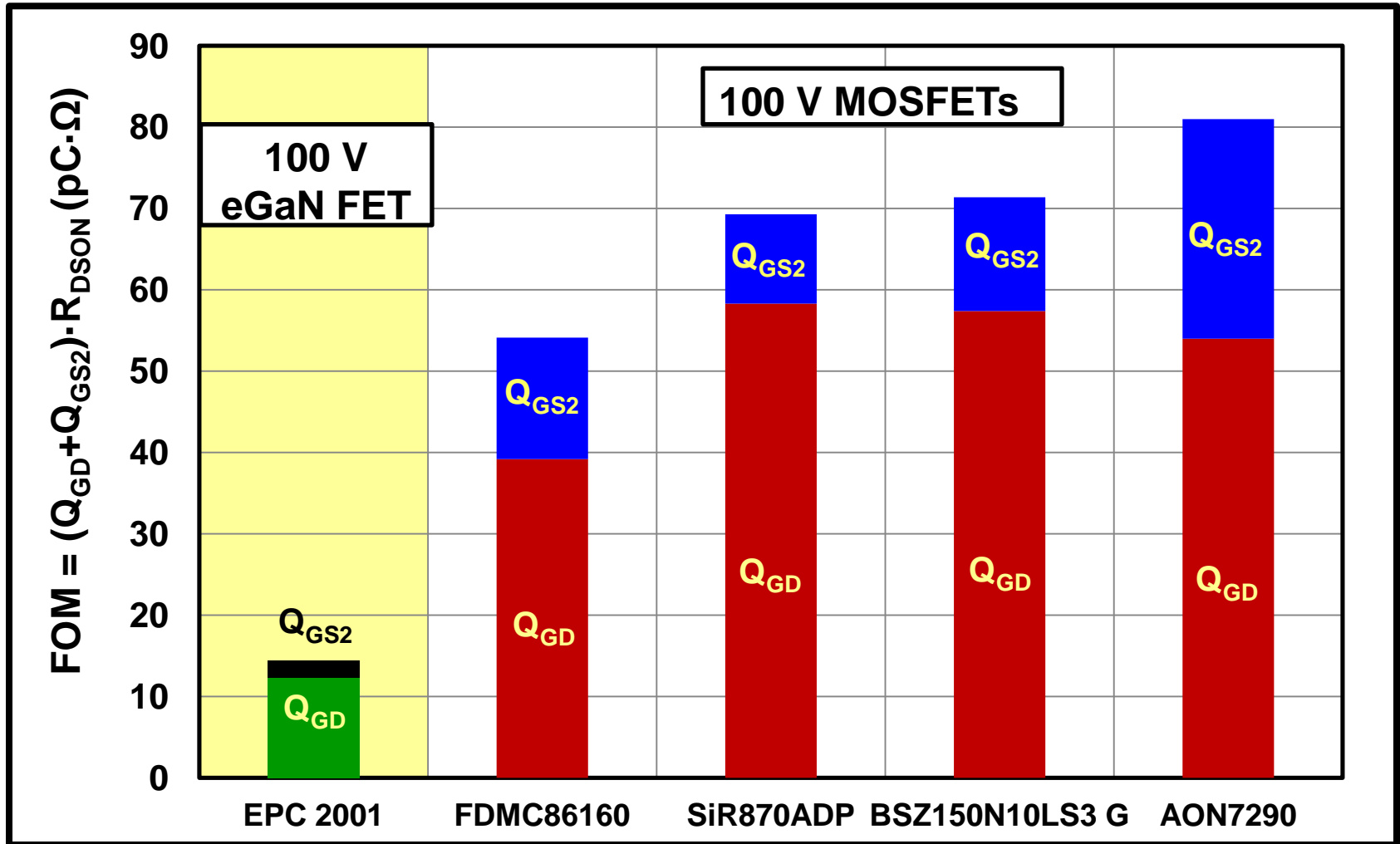
Ideal Hard Switching



$$P_{t_{VR}} \approx \frac{V_{IN} \cdot I_{OFF} \cdot Q_{GD} \cdot f_{sw}}{2 \cdot I_G}$$

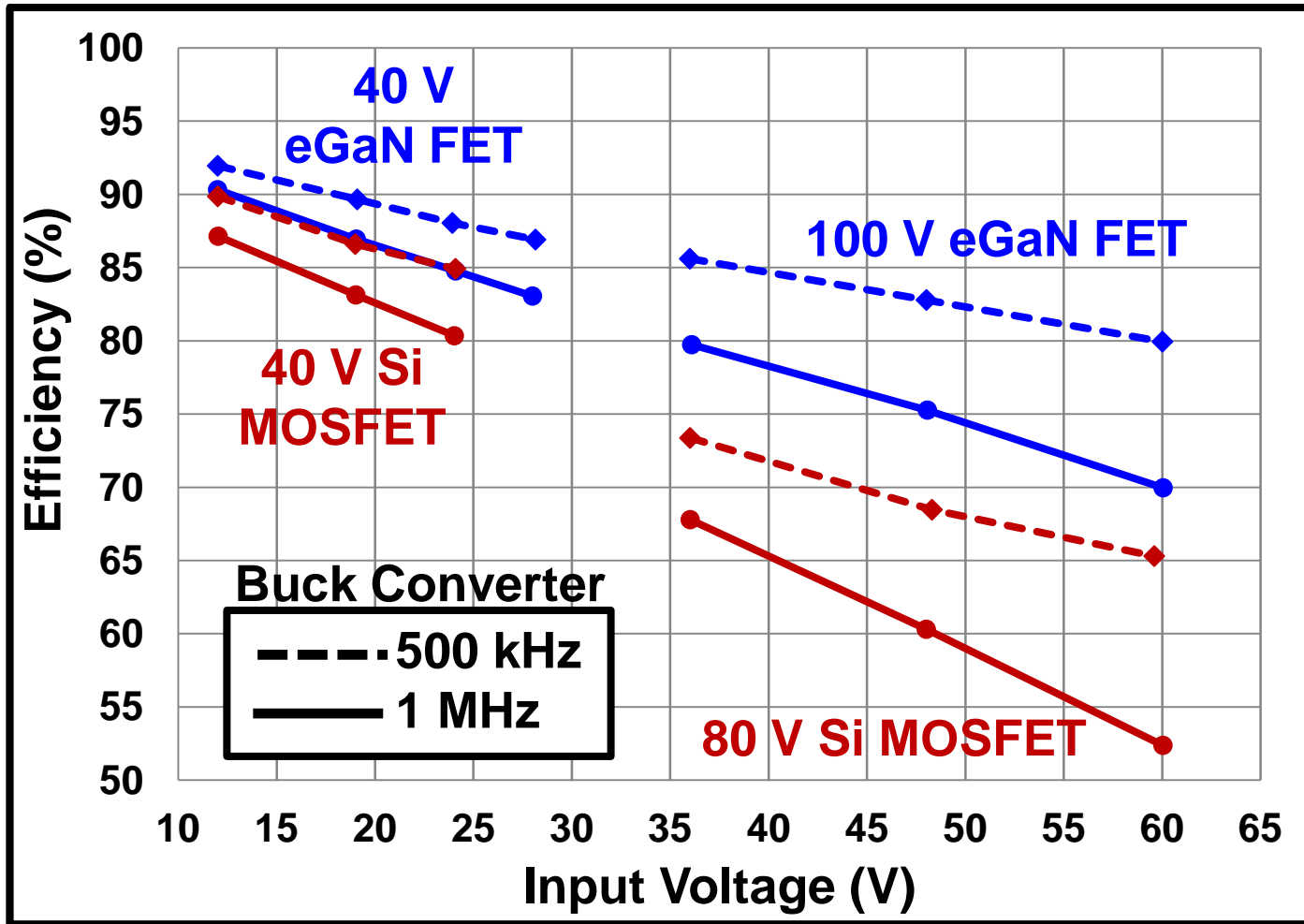
$$P_{t_{CF}} \approx \frac{V_{IN} \cdot I_{OFF} \cdot Q_{GS2} \cdot f_{sw}}{2 \cdot I_G}$$

100 V Device Comparison



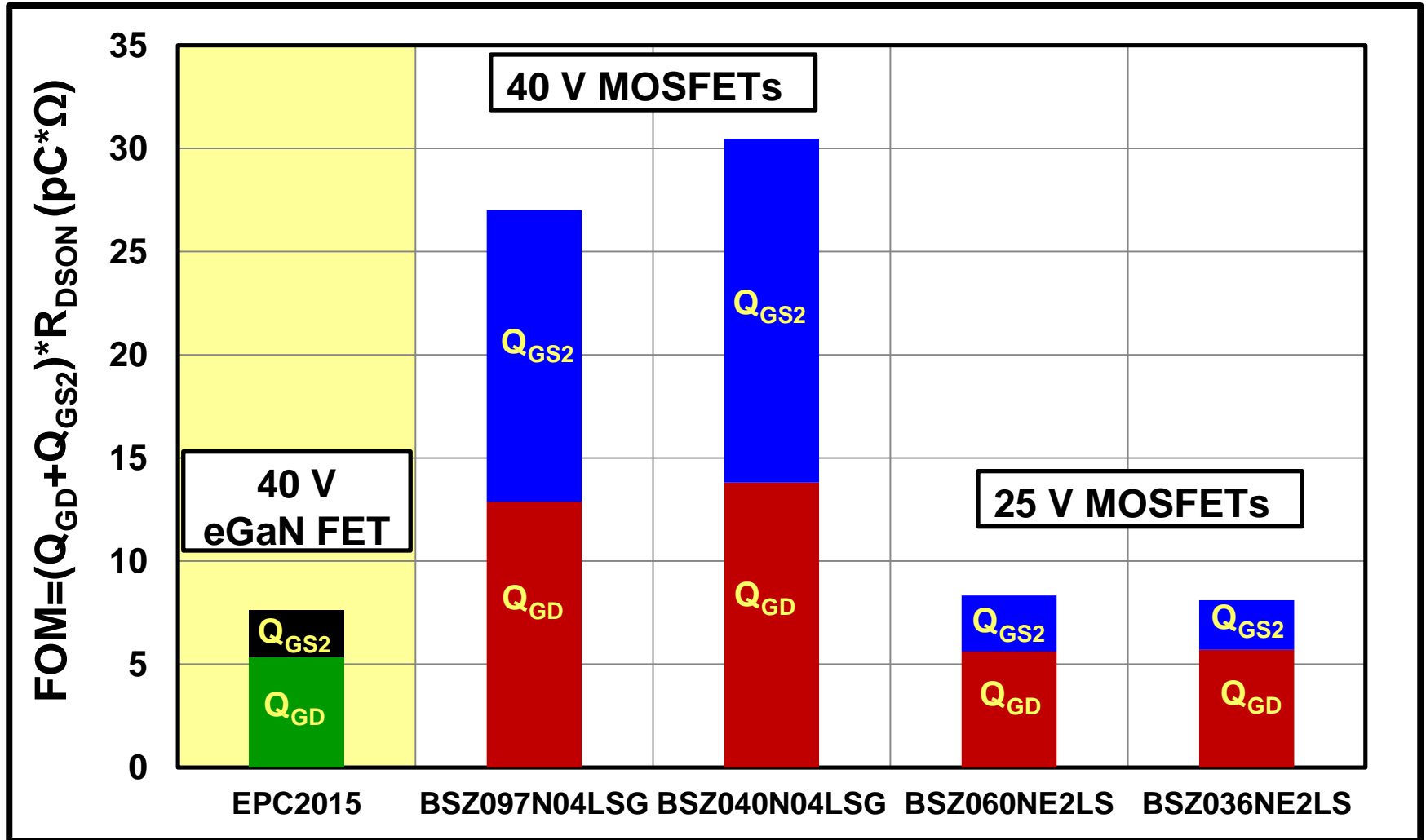
$$V_{DS} = 0.5 \cdot V_{DS}, I_{DS} = 10 \text{ A}$$

eGaN FET vs MOSFET



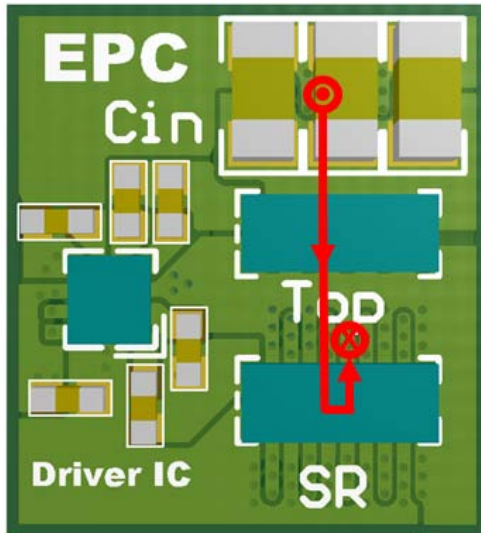
Measured Efficiency $V_{OUT}=1.2 V$ $I_{OUT}=10 A$

Low Voltage Device Comparison

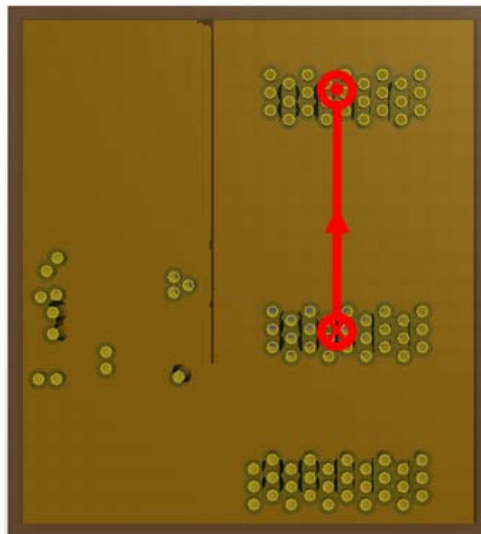
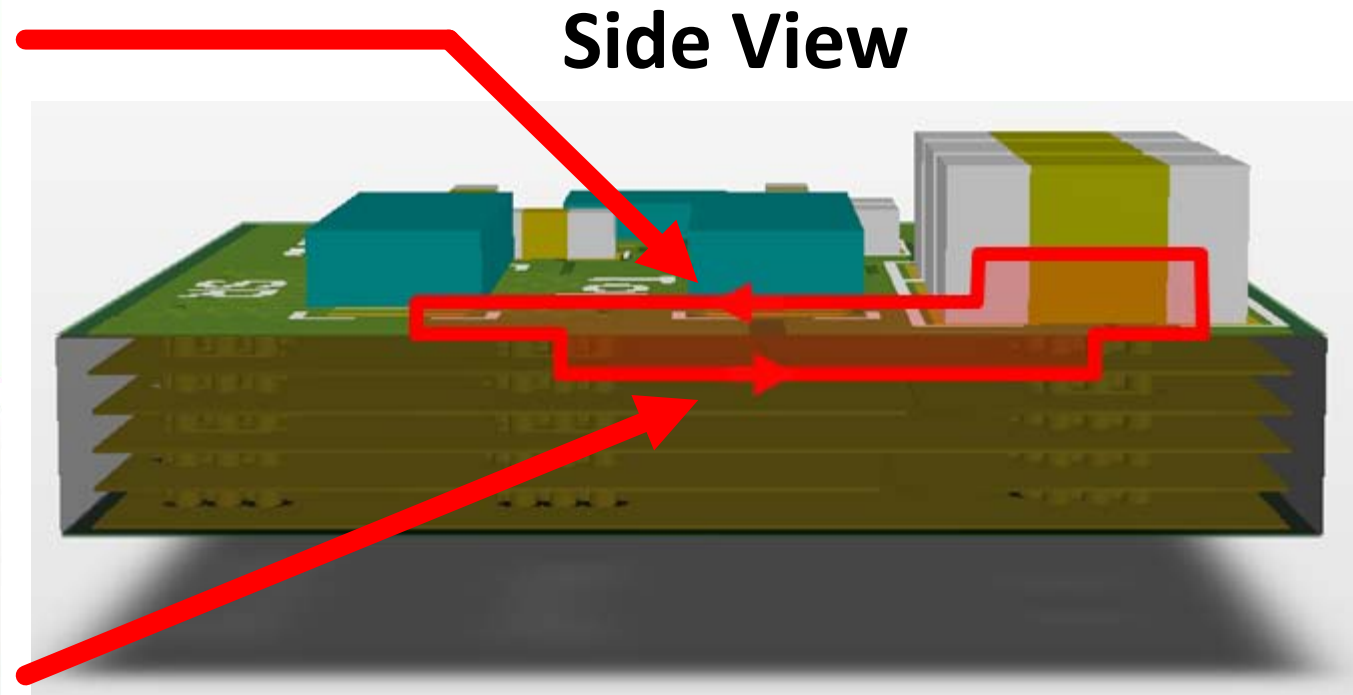


$V_{DS} = 12 \text{ V}, I_{DS} = 20 \text{ A}$

Optimal Layout



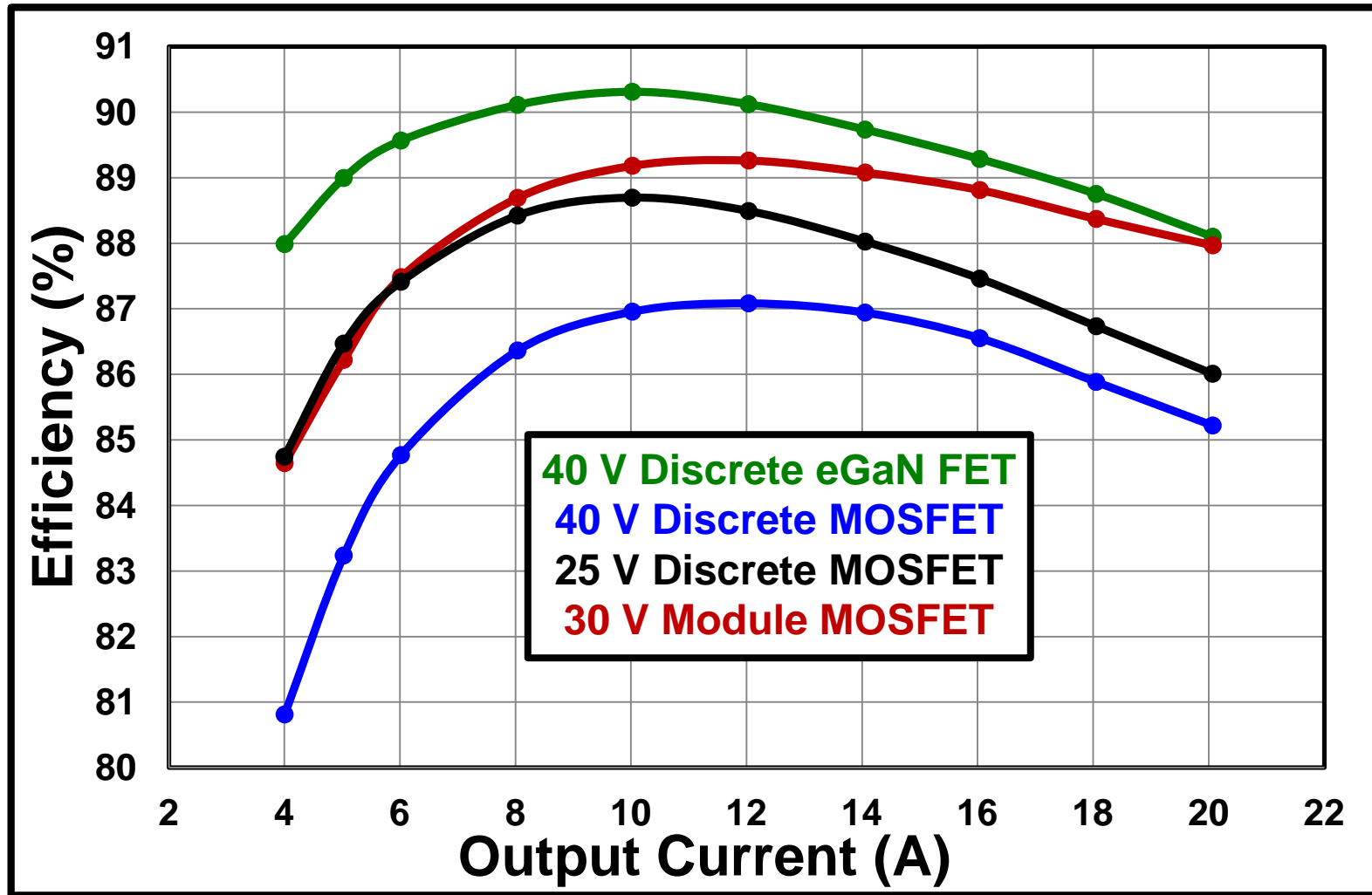
Top View



Top View Inner Layer 1

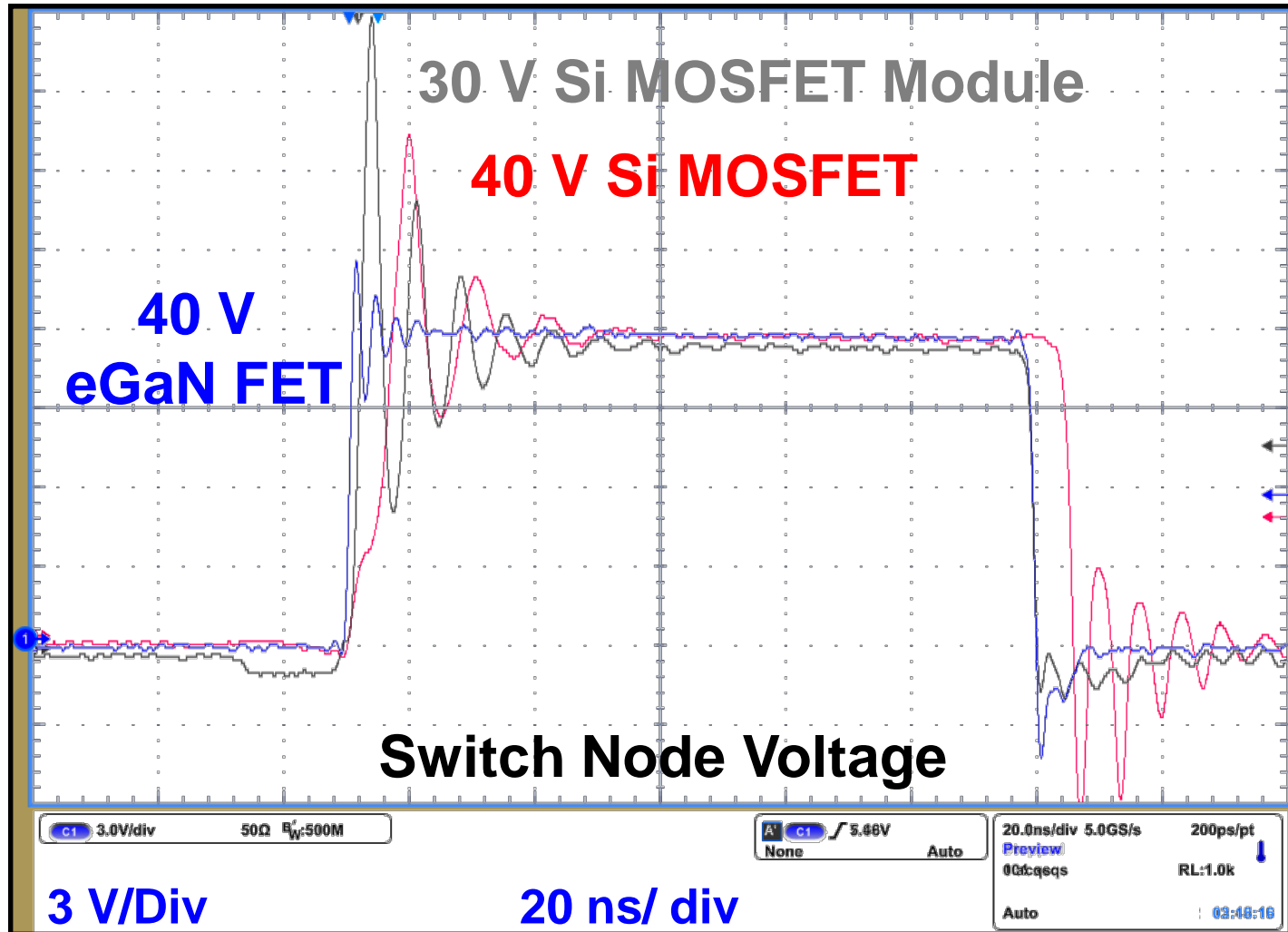
Ref: D. Reusch, J. Strydom,
“Understanding the Effect of PCB
Layout on Circuit Performance in a High
Frequency Gallium Nitride Based Point
of Load Converter,” APEC 2013

eGaN FET vs. MOSFET Efficiency



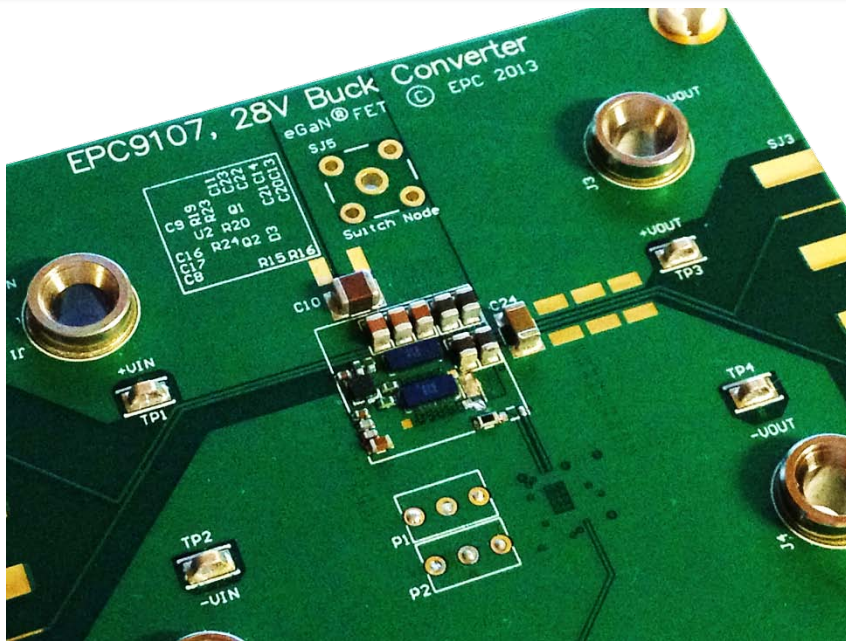
$V_{IN}=12\text{ V}$ $V_{OUT}=1.2\text{ V}$ $f_{sw}=1\text{ MHz}$ $L=300\text{ nH}$

Impact of Parasitics on Overshoot

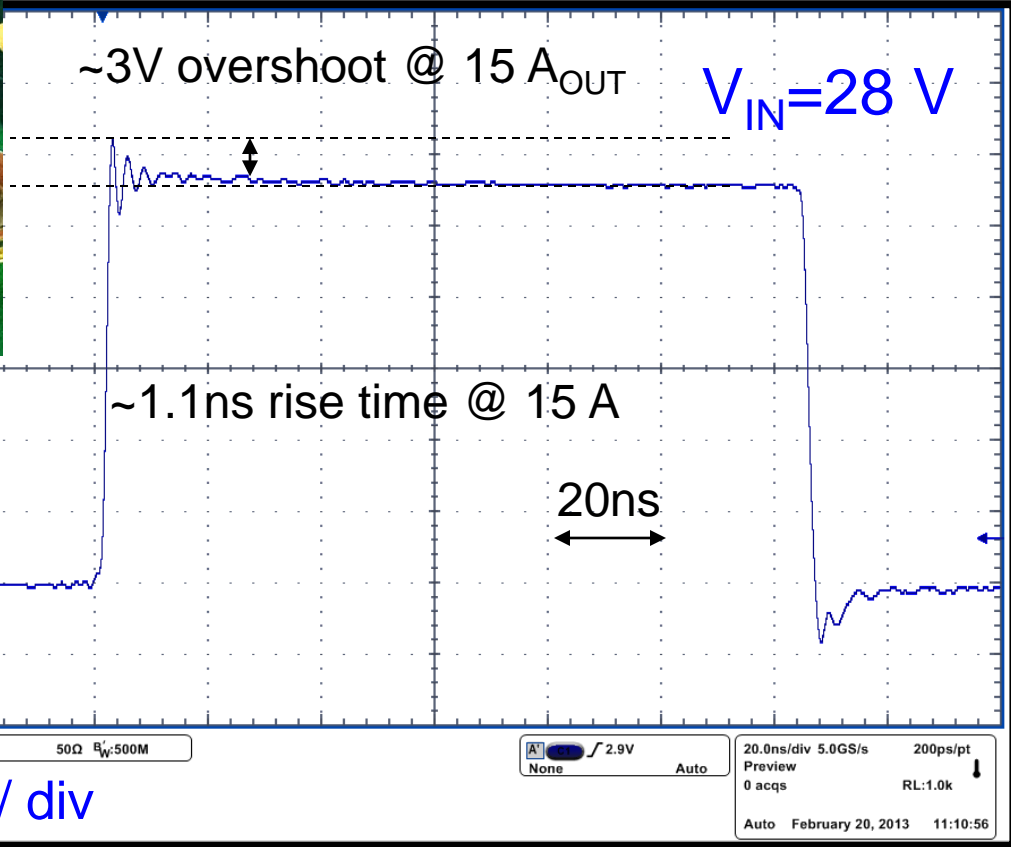


$V_{IN}=12\text{ V}$ $V_{OUT}=1.2\text{ V}$ $I_{OUT}=20\text{ A}$ $f_{sw}=1\text{ MHz}$ $L=300\text{ nH}$ eGaN FET T/SR: EPC2015
MOSFET T:BSZ097N04 SR:BSZ040N04 MOSFET Module: CSD97370Q5M

EPC9107 Demonstration Board



$V_{IN}=12-28\text{ V}$ $V_{OUT}=3.3\text{ V}$
 $I_{OUT}=15\text{ A}$ $f_{sw}=1\text{ MHz}$
2 x EPC2015

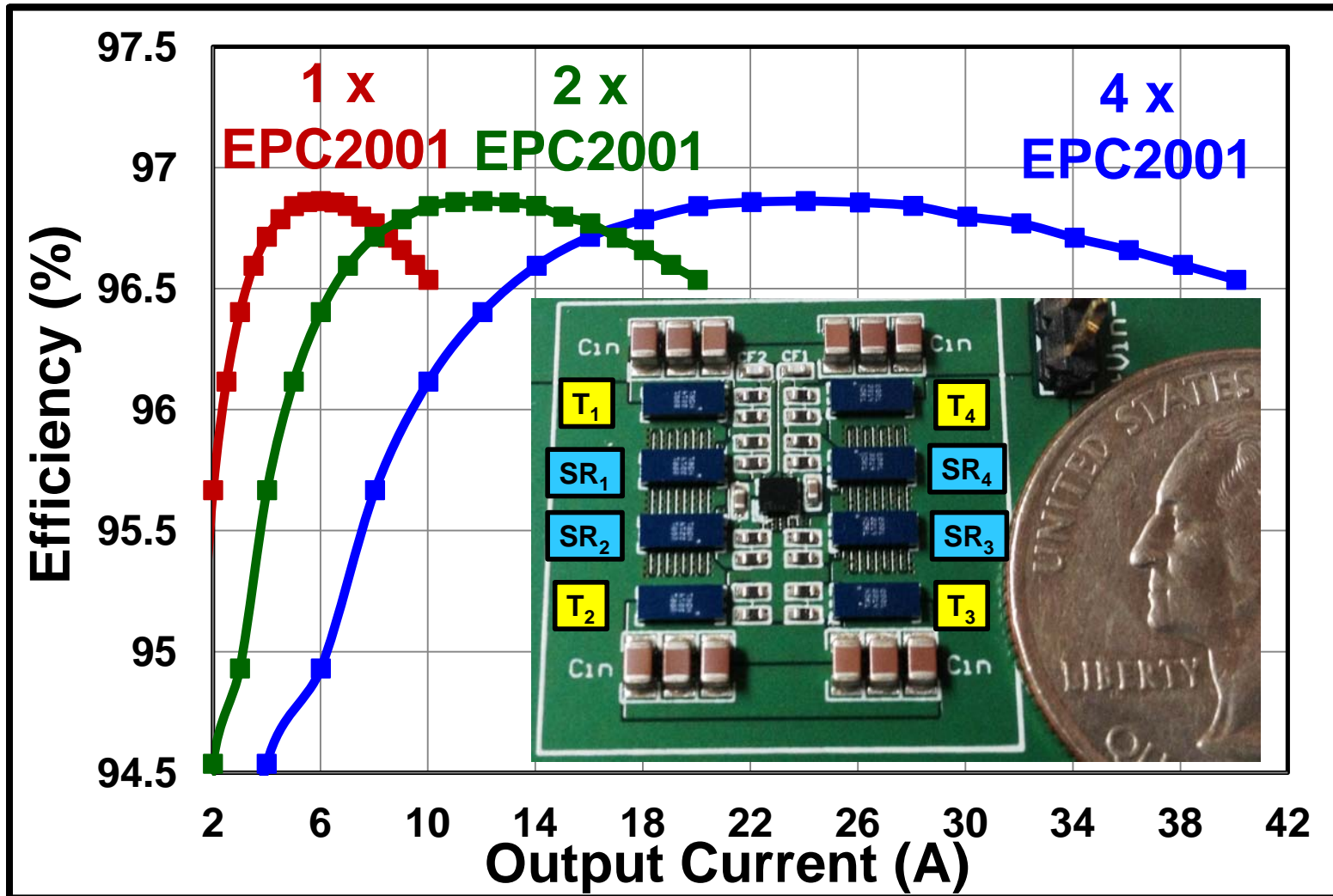


Switching Node Voltage

$V_{IN}=28\text{ V}$, $I_{OUT}=15\text{ A}$

5 V/ div

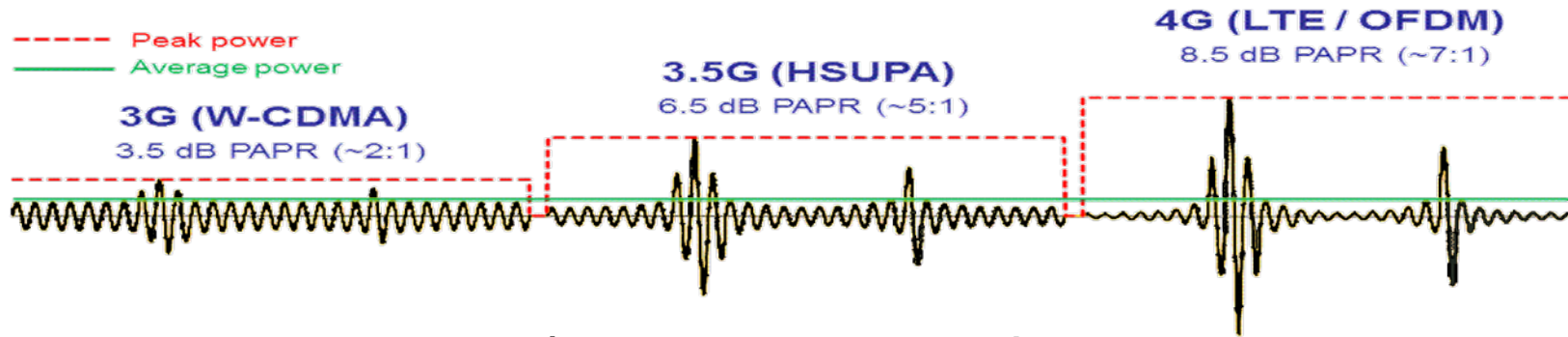
Higher Current?...Parallel



$V_{IN}=48\text{ V}$, $V_{OUT}=12\text{ V}$, $f_{sw}=300\text{ kHz}$

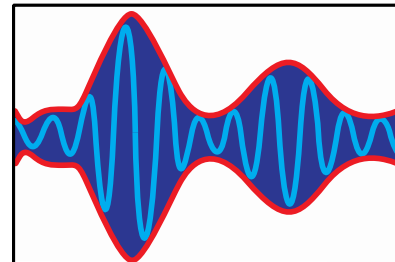
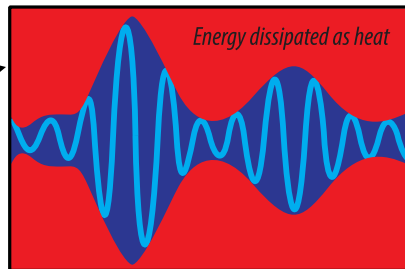
Envelope Tracking (ET)

Envelope Tracking



W/O ET

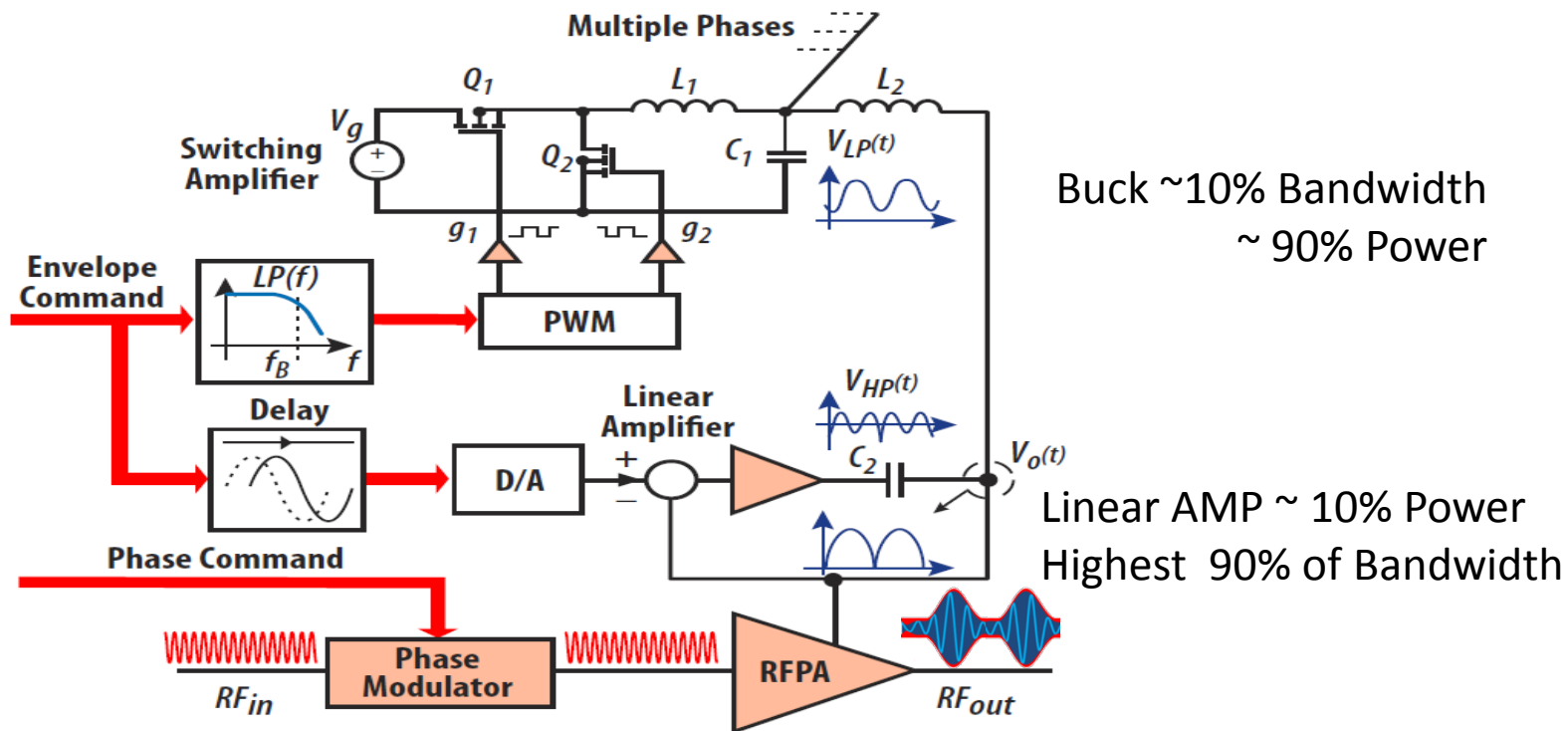
With ET



- Envelope Tracking can double base station efficiency.

Envelope Tracking Supply

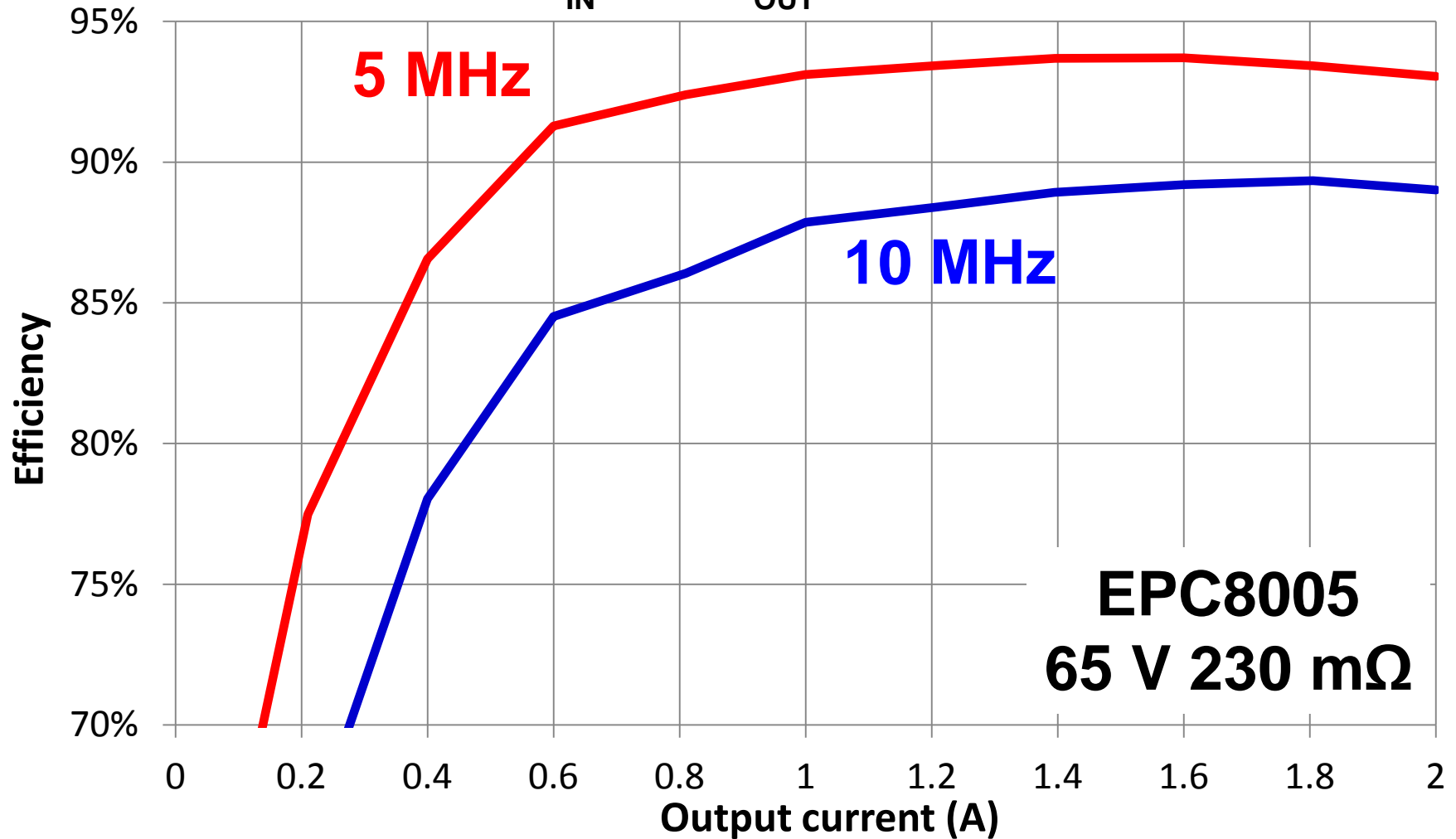
- ET power supply topologies vary
 - Hybrid / linear-assisted Buck* (one option)



* V. Yousefzadeh, et. al, "Efficiency optimization in linear-assisted switching power converters for envelope tracking in RF power amplifiers," ISCAS 2005

Efficiency

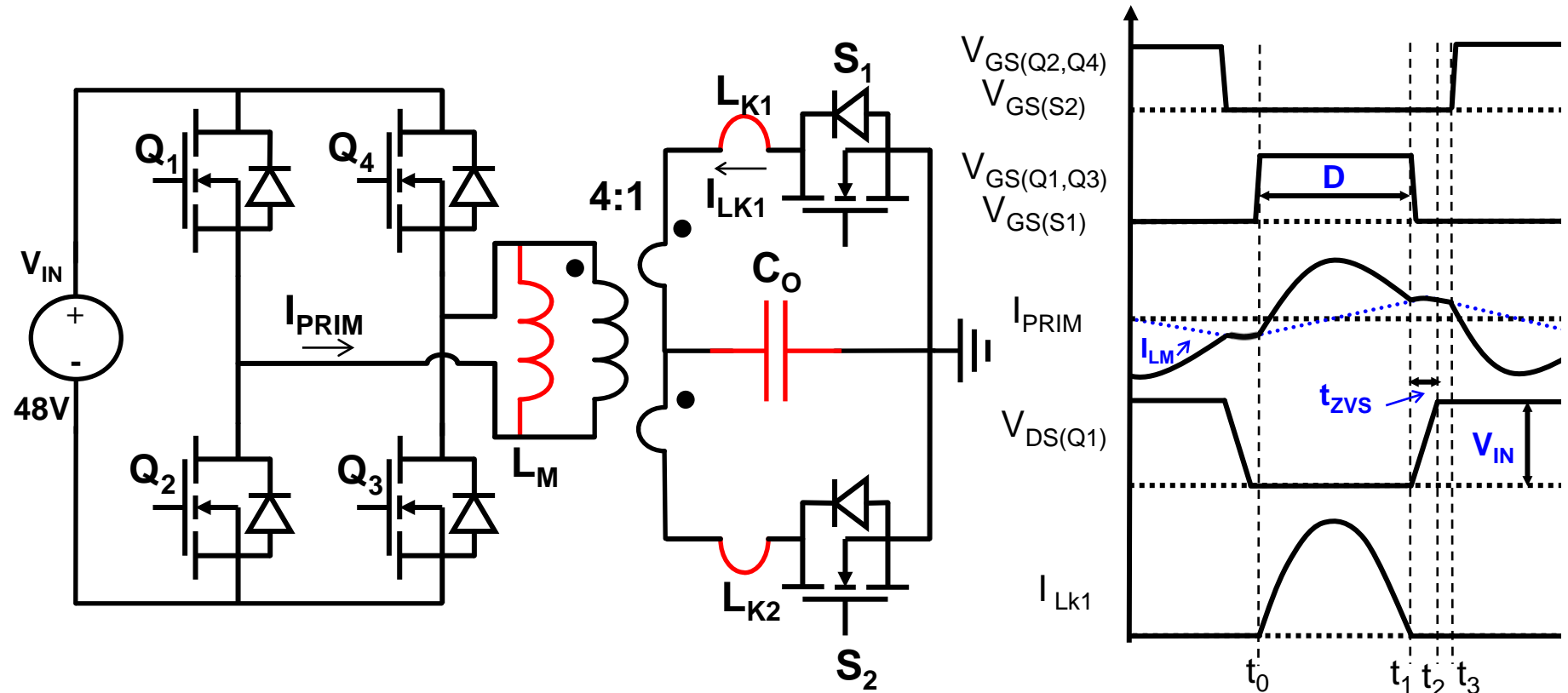
$V_{IN}=42\text{ V}$ $V_{OUT}=20\text{ V}$



Resonant Converters

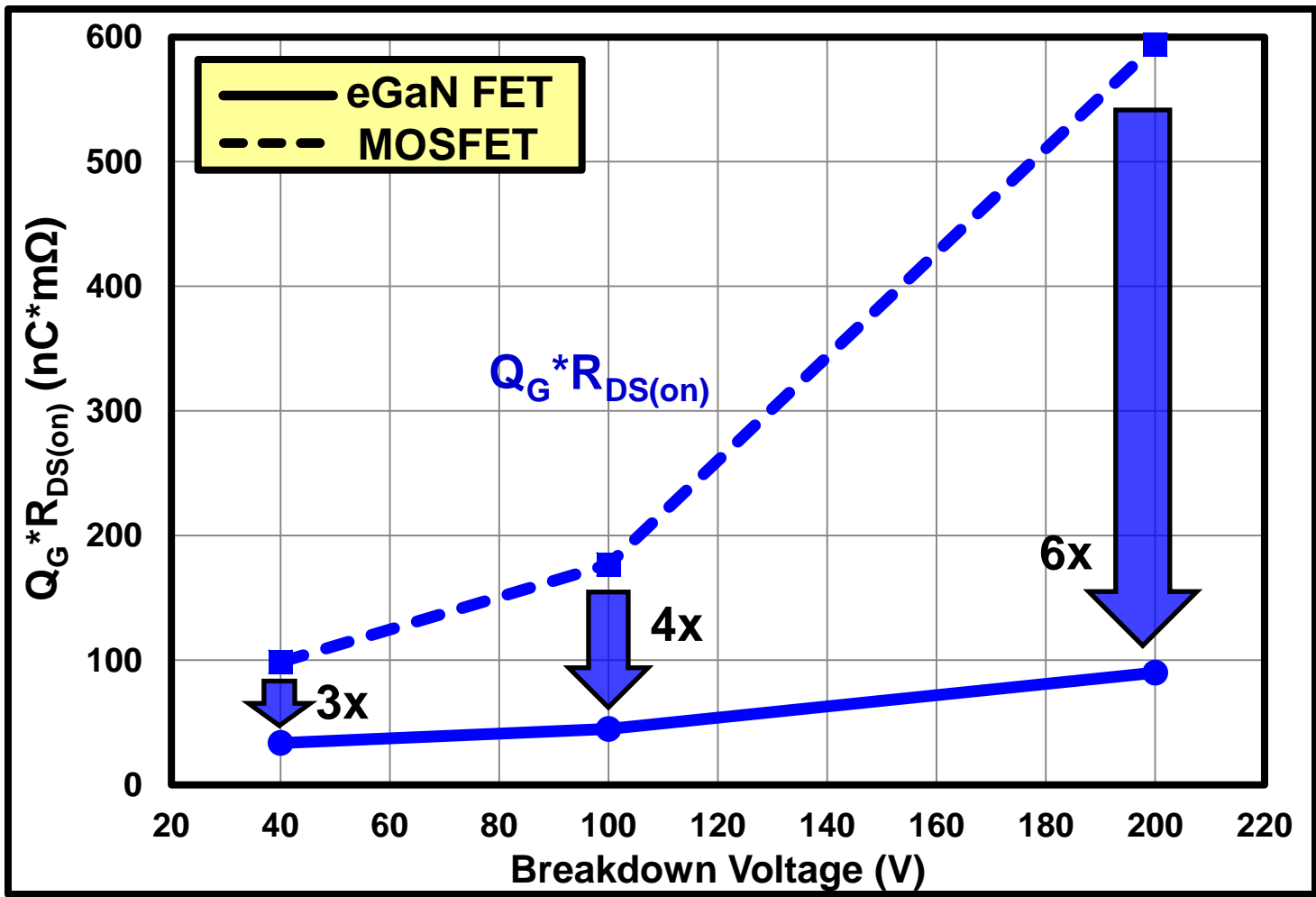
Resonant Bus Converter

High Frequency DC/DC Transformer

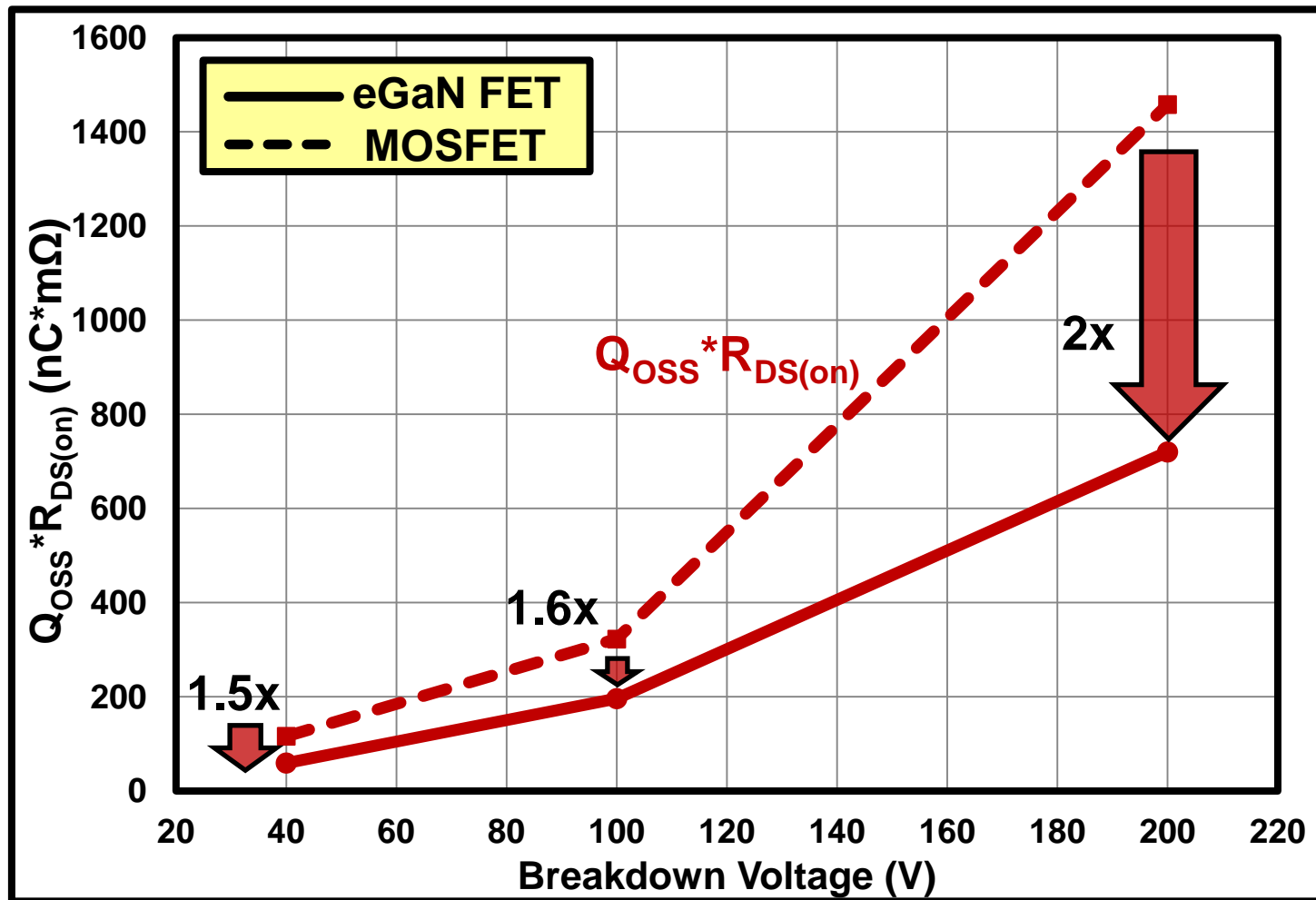


Ref: Y. Ren, M. Xu, J. Sun, and F. C. Lee, "A family of high power density unregulated bus converters," IEEE Trans. Power Electron., vol. 20, no. 5, pp. 1045–1054, Sep. 2005.

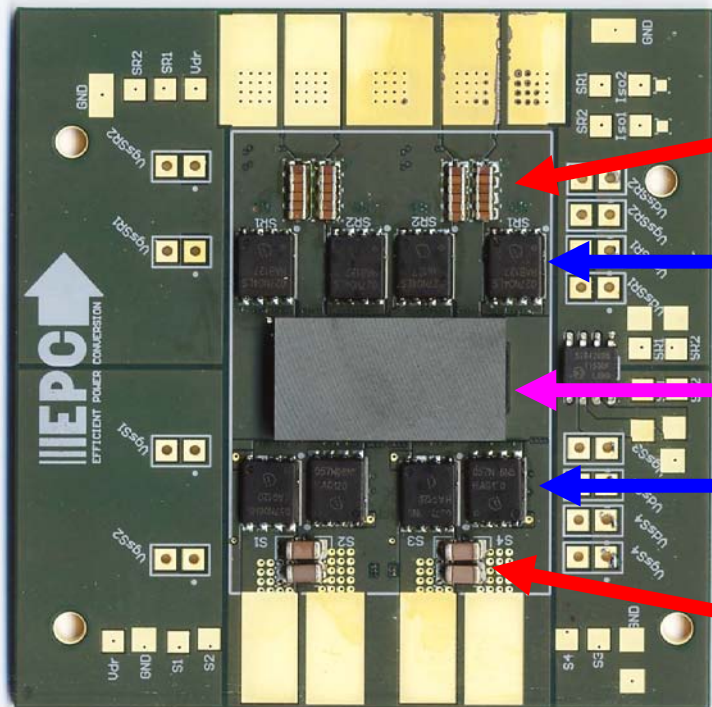
Gate Charge



Output Charge



eGaN FET vs. MOSFET



MOSFET

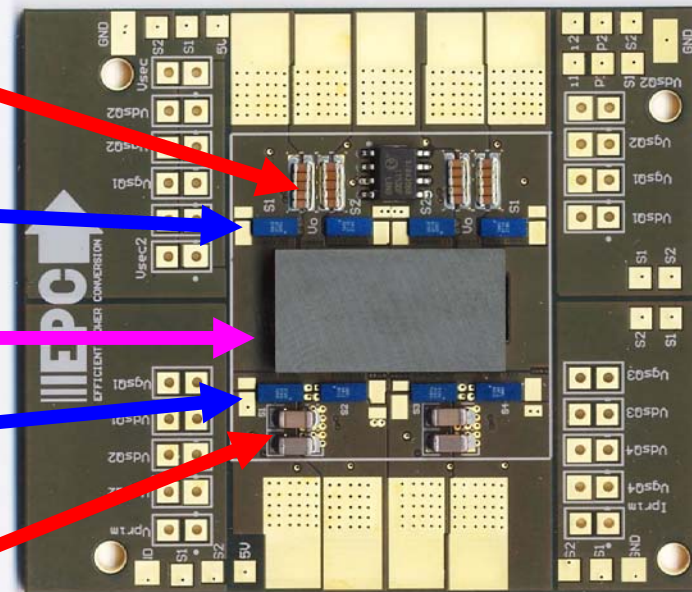
Resonant Capacitors

Secondary Devices

Transformer

Primary Devices

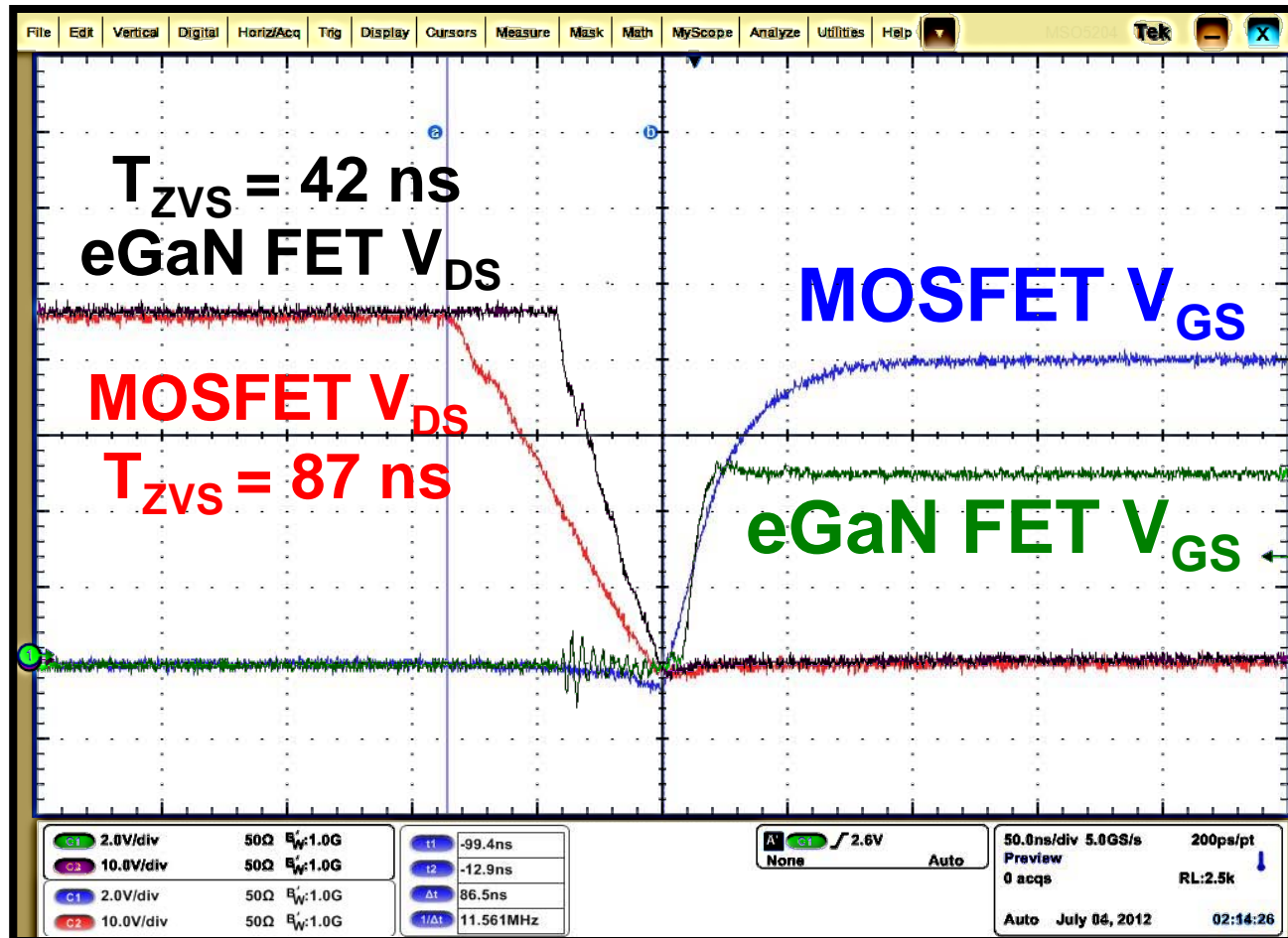
Input Capacitors



eGaN[®]FET

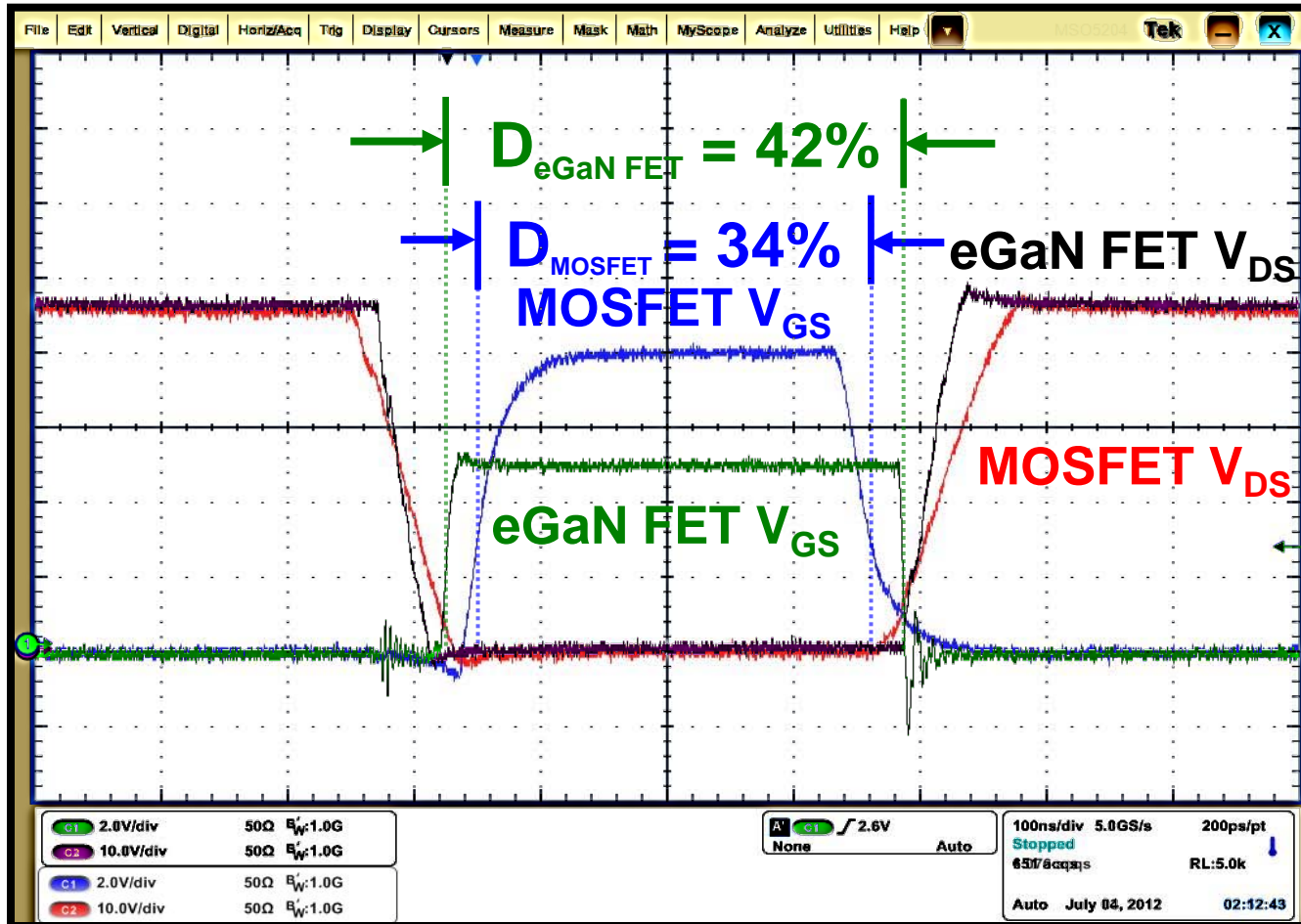
vs.

ZVS Switching Comparison



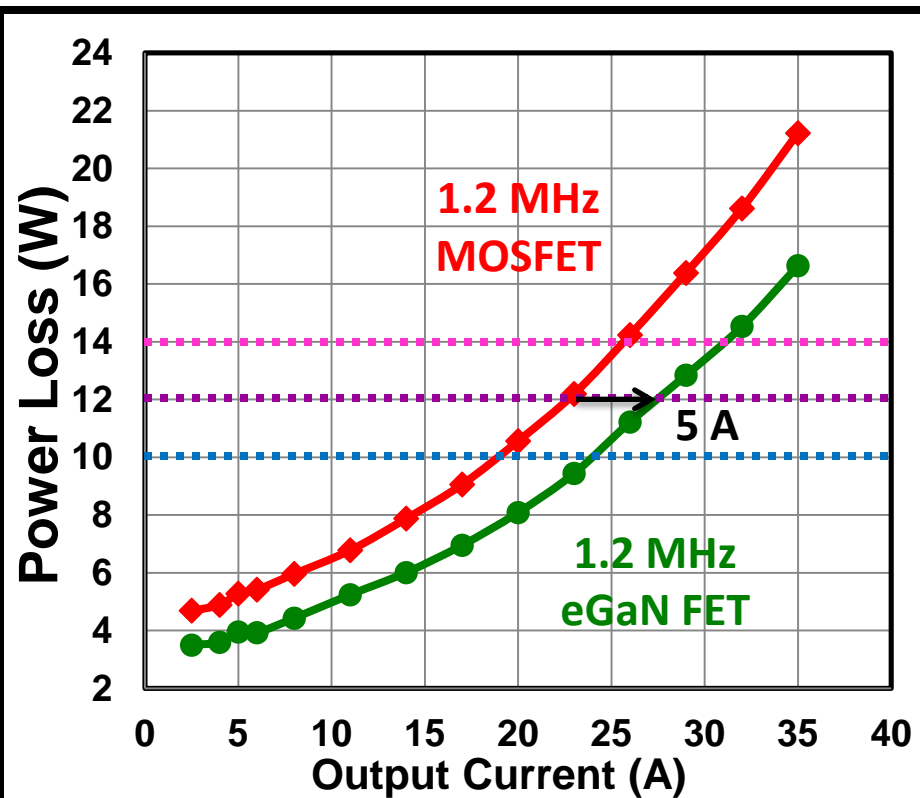
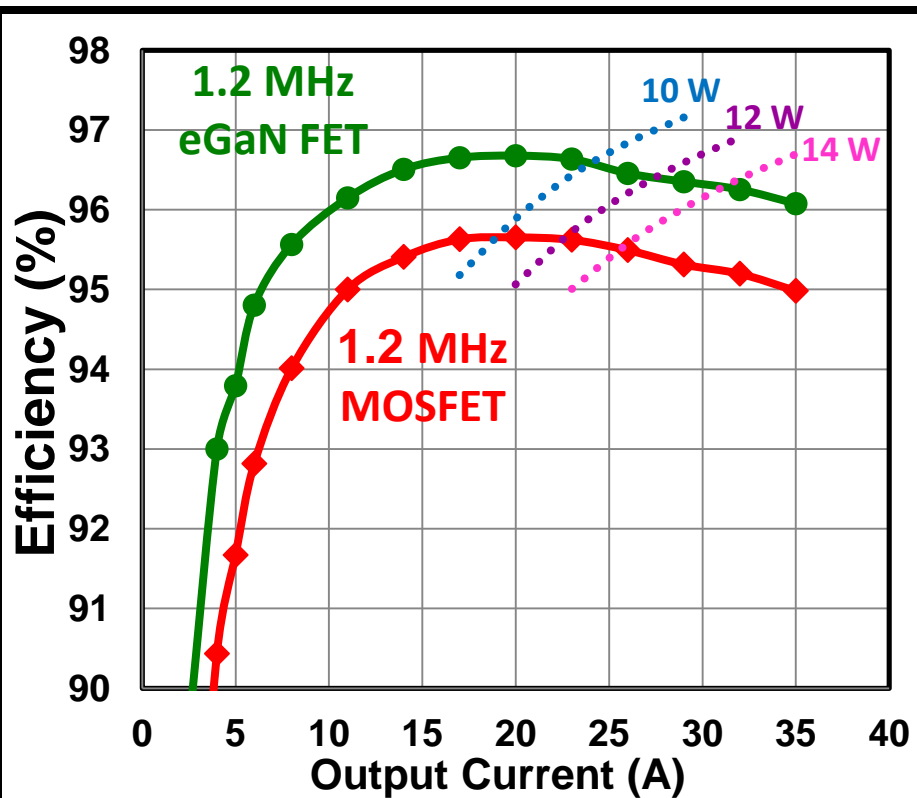
$$f_{sw} = 1.2 \text{ MHz}, V_{IN} = 48 \text{ V}, \text{ and } V_{OUT} \approx 12 \text{ V}$$

Duty Cycle Comparison



$$f_{sw} = 1.2 \text{ MHz}, V_{IN} = 48 \text{ V}, \text{ and } V_{OUT} = 12 \text{ V}$$

Efficiency Comparison



$$f_{sw} = 1.2 \text{ MHz}, V_{IN} = 48 \text{ V}, \text{ and } V_{OUT} \approx 12 \text{ V}$$

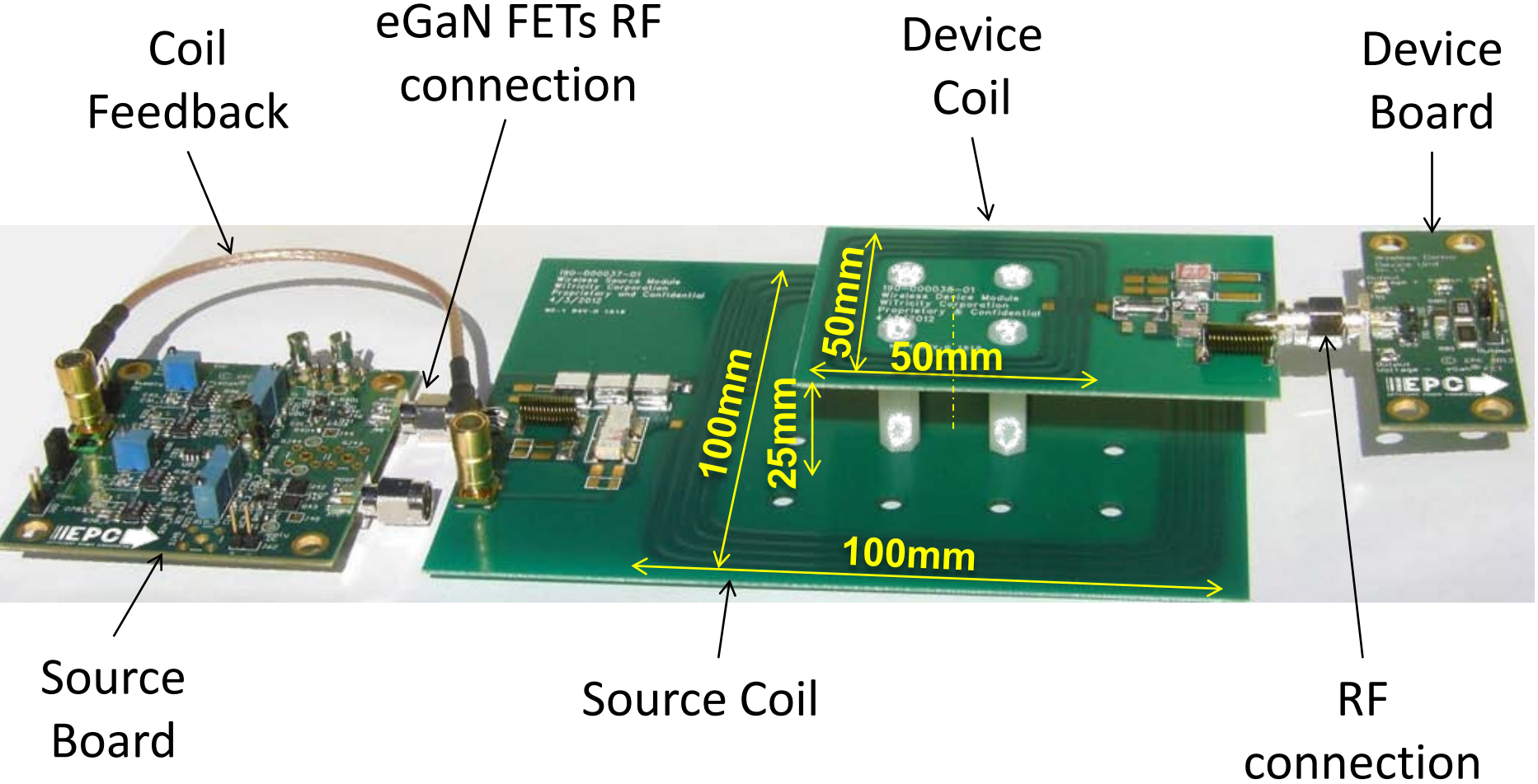
- eGaN FETs improve high frequency resonant converter performance
 - Lower output charge
 - Lower gate charge
 - More power delivery per cycle

Why Wireless Power?



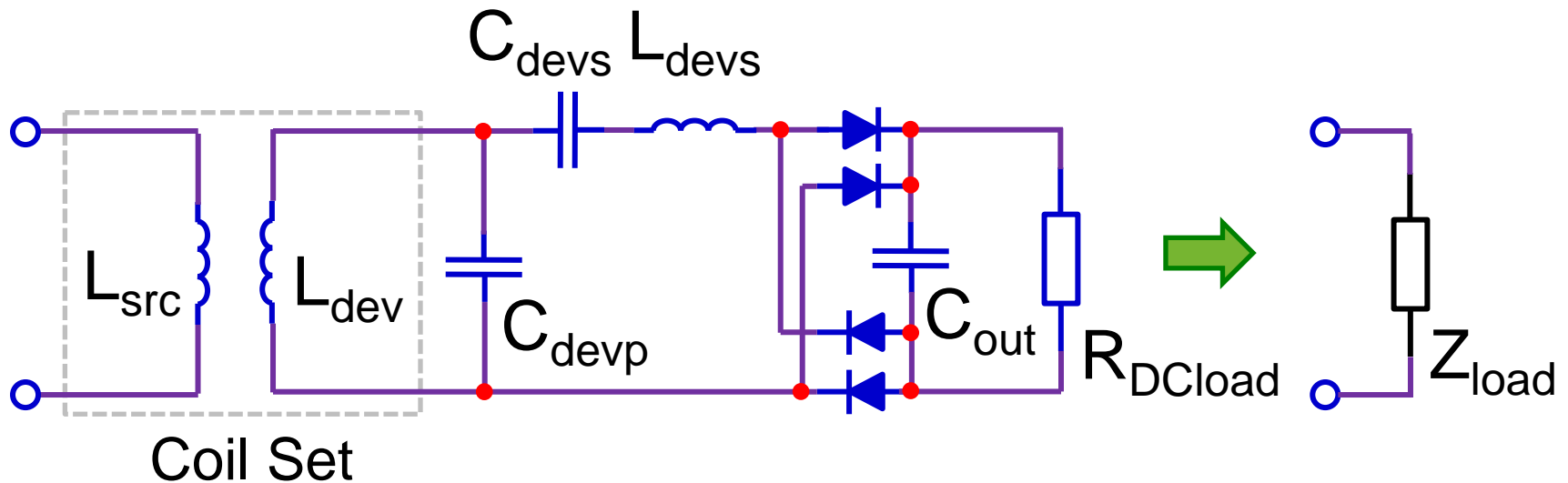
- eGaN FETs enable higher efficiency and operation at safer frequencies
- The global wireless charging market is estimated to grow to \$10B by 2018, a CAGR of 42.6%

Experimental System Setup



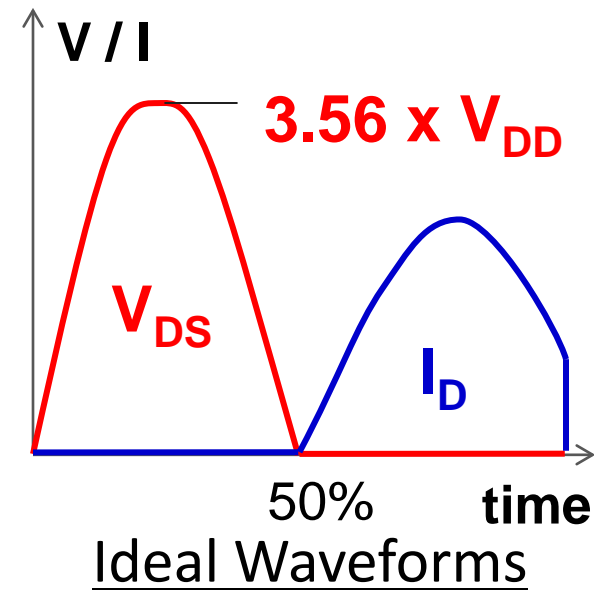
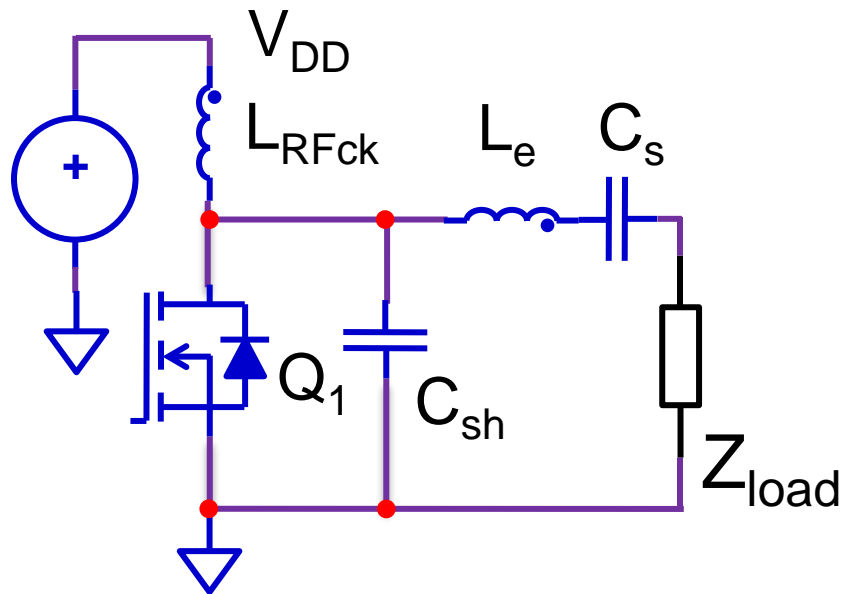
Wireless Coil-set Overview

Simplified representation of coil-set for easy comparison between topologies



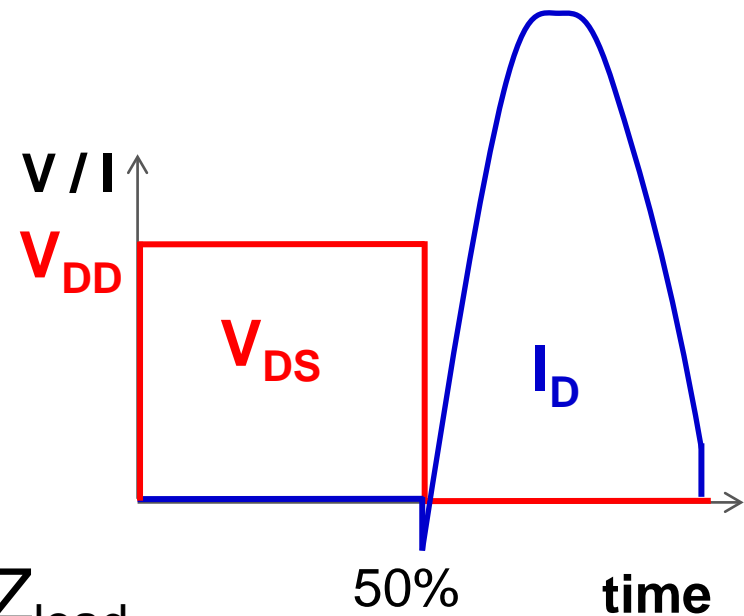
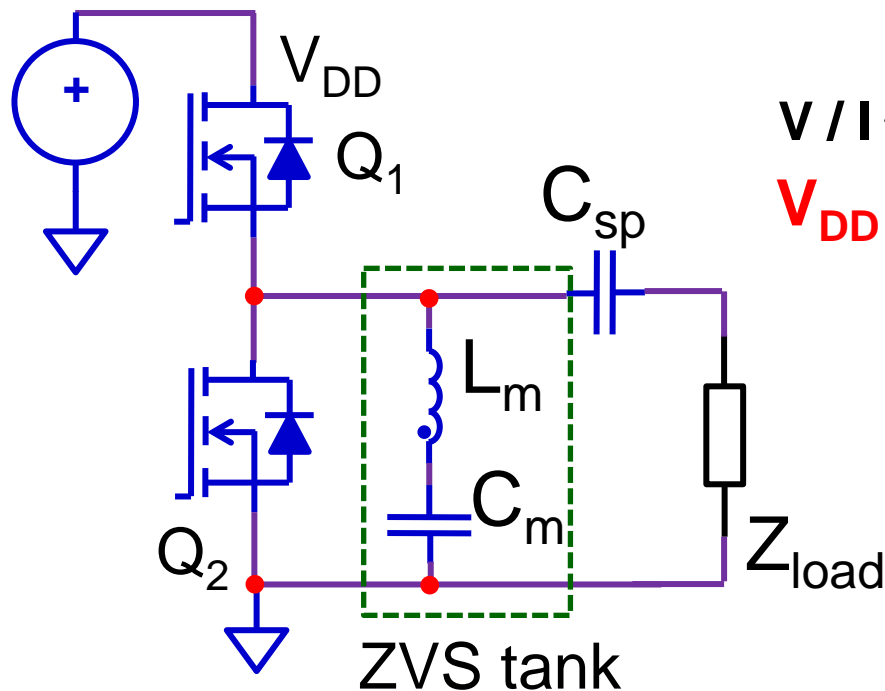
Class E Overview

- Switch voltage rating = $> 3.56 \cdot \text{Supply } (V_{DD})$.
- C_{OSS} “absorbed” into matching network.



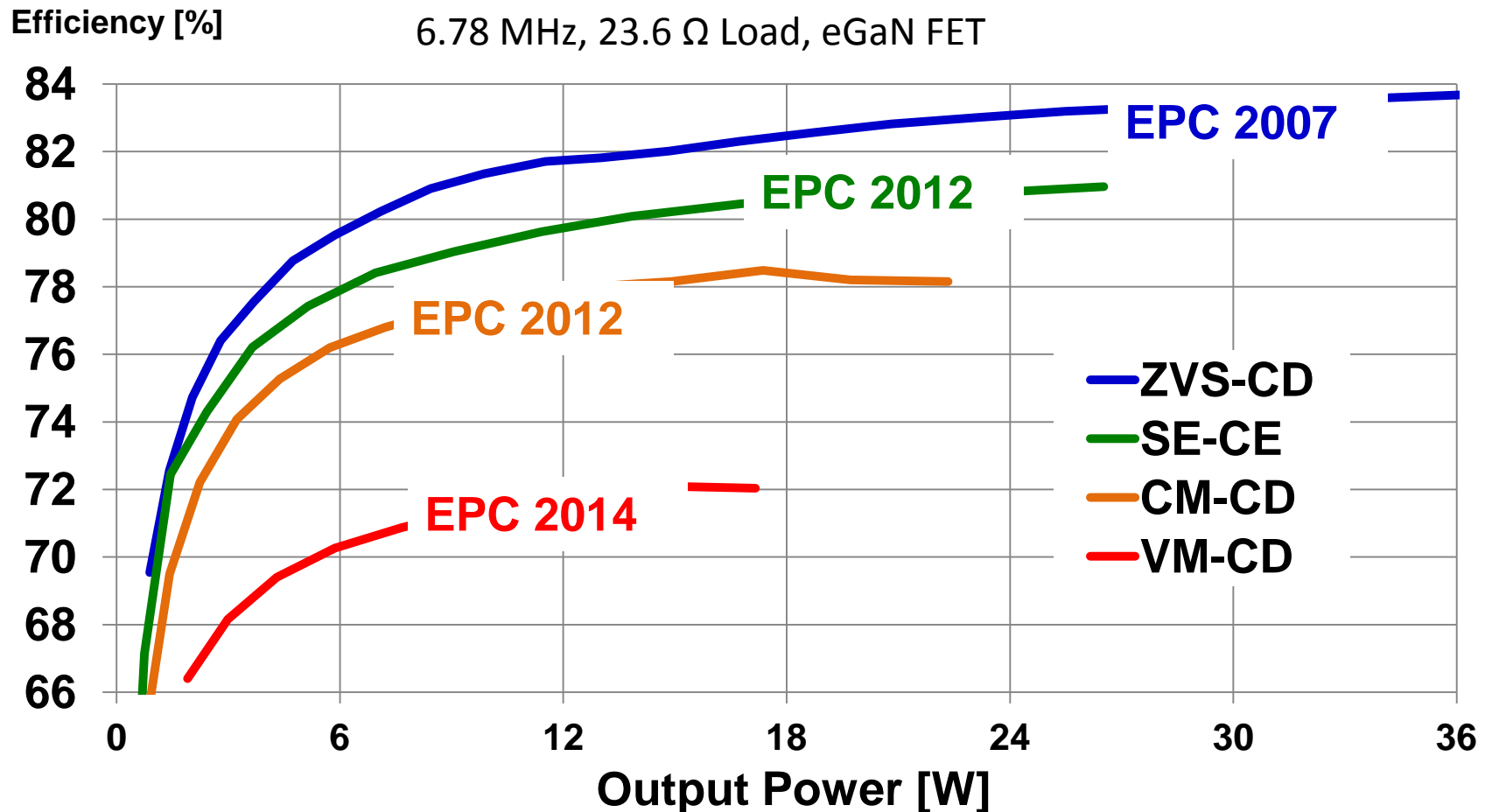
ZVS Voltage Mode Class D

- C_{OSS} Voltage is transitioned by the ZVS tank
- Lower eGaN FET C_{OSS} leads to higher available duty cycle
- Highest system efficiency



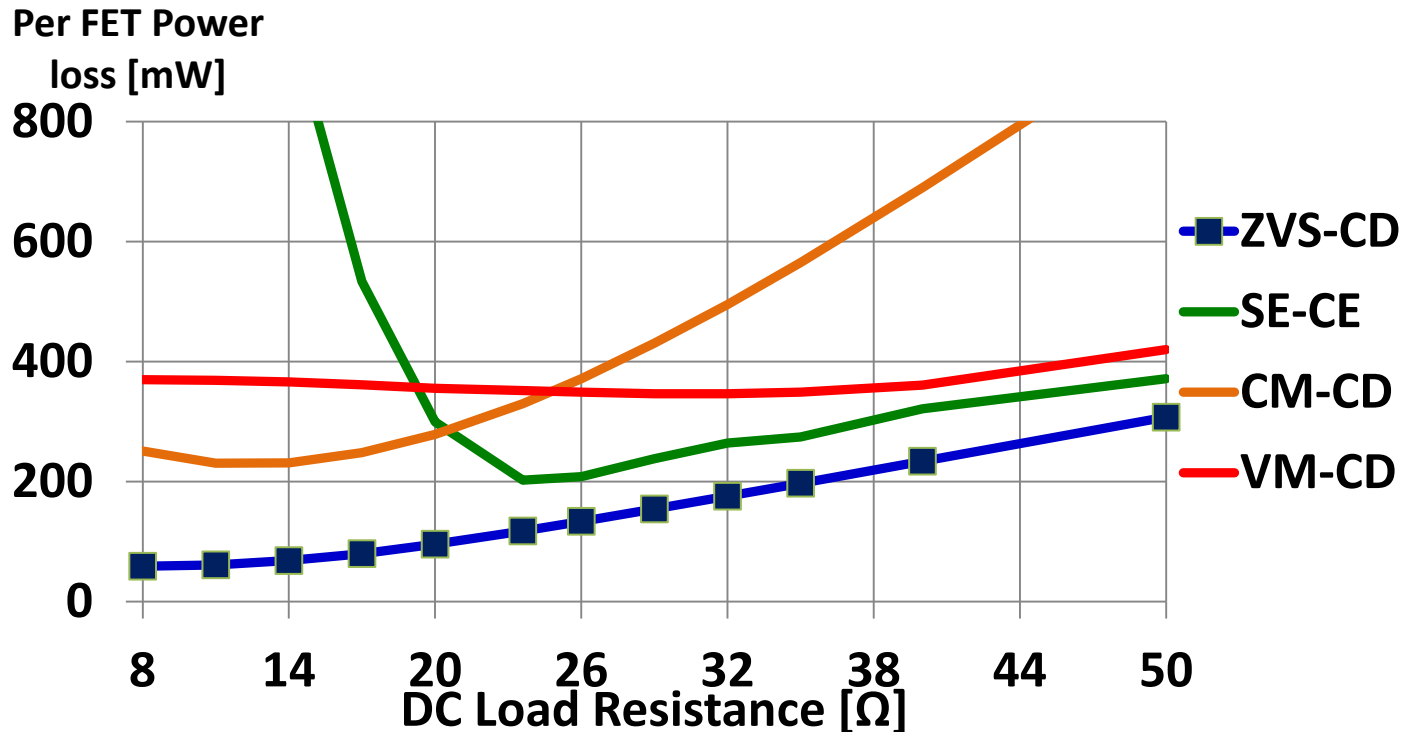
Ideal Waveforms

Efficiency



eGaN FETs enable the highest efficiency in all topologies using 6.78 MHz and 13.56 MHz frequencies.

Impact of Load



ZVS class D has higher efficiency and a broader operating range than class E.

A Look into the Future

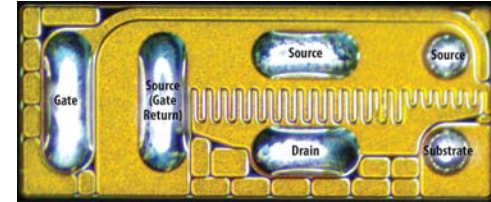
Silicon vs. eGaN Transistor Costs

	2013	2016
Starting Material	lower	lower
Epi Growth	<i>higher</i>	<i>~same?</i>
Wafer Fab	lower	lower
Test	same	same
Assembly	lower	lower
OVERALL	higher	<i>lower!</i>

EPC Into the Future

Ultra High Frequency Family
1 - 3 GHz

Launched Sept 2013



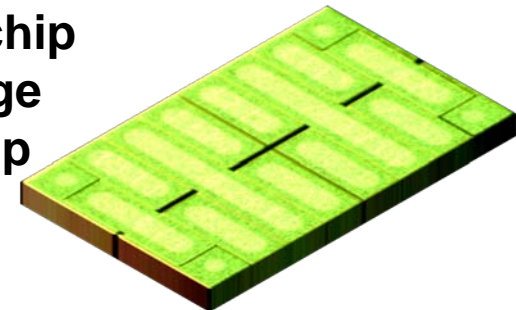
Mass Production
40 V - 200 V
~500 MHz

Higher Current
45 A

Higher Voltage
600 V

More functions on a chip
Monolithic half bridge
Driver on power chip

Next Generation Devices
2 x FOM Improvement



eGaN FETs...

- enable exciting new applications
- have the potential to replace silicon power MOSFETs
- are straightforward to use, but they can't just drop them into a MOSFET socket. Some R&D is needed – **start today!**